



# **ECE 621**

## **Signaling & Synchronization**

### **Fall 2020**

#### **Topic 2**

## **I/O Channel Characteristics**

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**ICL**

**(Courtesy of S. Pamarti – UCLA, S. Palermo – TAMU,  
E. Alon – UCB, and W. Dally – Stanford)**

# Outline

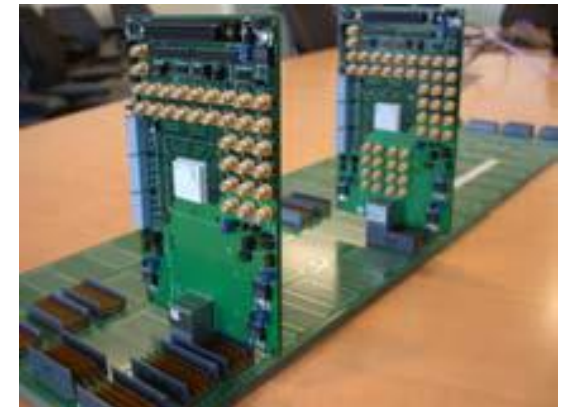
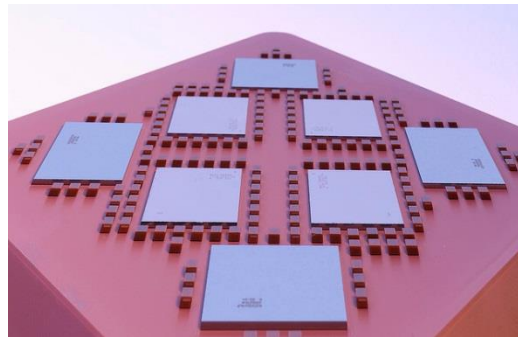
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- **Channel Components**
  - Wires (PCB traces, Co-axial cables, twisted pairs, ..etc.)
  - IC Packages
  - Vias
  - Connectors
- **Channel Impairments**
  - Limited Bandwidth - Loss
  - Reflections
  - Cross-Talk
- **Channel Representations**
  - Impulse Response
  - S-Parameters
  - Eye Diagram
  - Time-Domain Reflectometry (TDR)

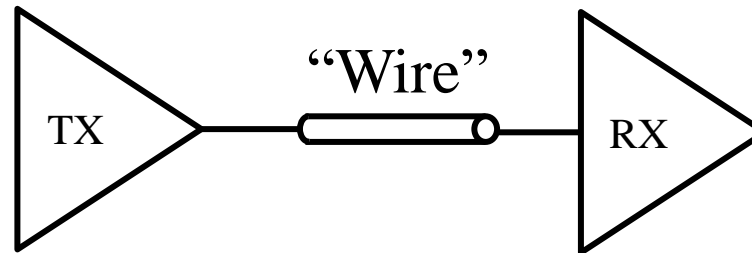


# Chip-to-Chip Communication Channels

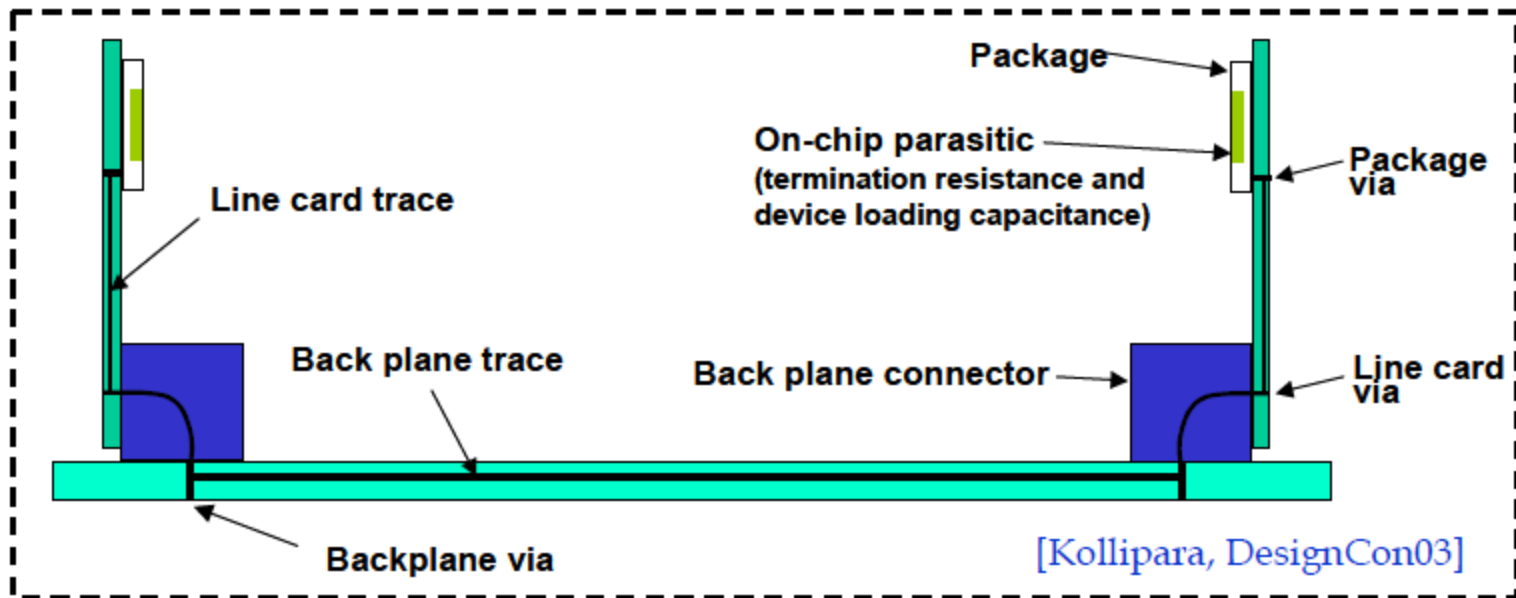
- **Short Range**
  - ICs on the same PCB
  - The PCB could be within a multi-chip module
- **Long Range**
  - ICs on different PCBs
  - PCBs connected through another board or a co-axial cable



# Channel Complexity



Neglected for low data-rates, short lengths and simple architecture  
Otherwise



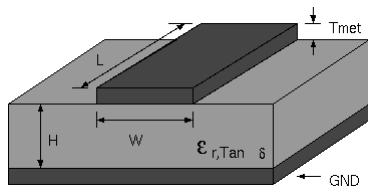
# Example Wires

## Cables

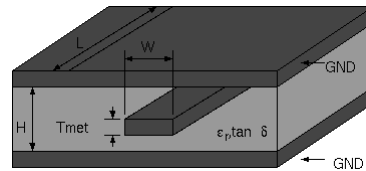


Coaxial Flat or Ribbon Twisted Pair Flex Circuit

## PCB Traces



Micro-strip



Strip-line

TABLE 2-2 American Wire Gauges and Their Properties

Gauge (AWG)	Wire Diameter (mils)	Wire Diameter (mm)	DC Resistance ( $\times 10^{-3} \Omega/\text{m}$ ) <sup>a</sup>	Maximum Current (A)	Attenuation at 1 GHz (dB/m)
000	409.6	10.404	0.203	175	0.02
0	324.9	8.252	0.322	125	0.03
4	204.3	5.189	0.815	70	0.04
6	162.0	4.115	1.297	50	0.06
8	128.5	3.264	2.061	35	0.07
10	101.9	2.588	3.277	25	0.09
12	80.81	2.053	5.210	20	0.11
14	64.08	1.628	8.268	15	0.14
18	40.30	1.024	20.95	5	0.22
20	31.96	0.8118	33.31	3	0.28
22	25.35	0.6439	52.95		0.35
24	20.10	0.5105	84.22		0.45
28	12.64	0.3211	213.0		0.71
30	10.03	0.2548	338.2		0.90
32	7.950	0.2019	538.4		1.13
34	6.310	0.1602	854.6		1.42

<sup>a</sup>For annealed copper at 20°C.

<sup>b</sup>Skin-effect frequency.

$$AWG = -10 \ln \left( \frac{A}{A_0} \right)$$

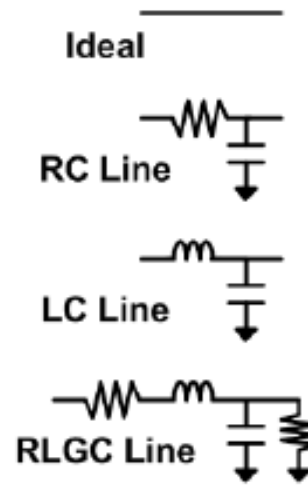
[Dally]

Type	W	R	C	L
On chip	0.6μm	150kΩ/m	200pf/m	600nH/m
PC Board	150μm	5Ω/m	100pf/m	300nH/m
24AWG pair	511μm	0.08Ω/m	40pf/m	400nH/m

# Wire Models

- **Model Types**

- Ideal
- Lumped C, R, L
- RC transmission line
- LC transmission line
- RLGC transmission line



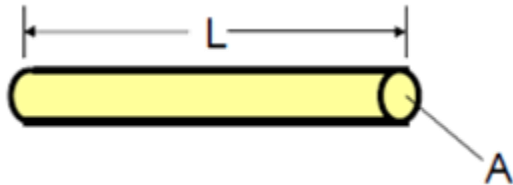
- **Condition for LC or RLGC model (vs RC)**

$$f_0 \geq \frac{R}{2\pi L}$$



# Basic Electrical Properties of Wires

- Resistance



$$R = \frac{\rho L}{A}$$

Material	$\rho$ (n $\Omega$ -m)
Ag	16
Cu	17
Au	22
Al	27

- Capacitance

$$C = \frac{\pi\epsilon}{\log\left(\frac{s}{r}\right)}$$

A diagram showing two small blue circles representing parallel plates. They are separated by a vertical double-headed arrow labeled 's'. The radius of the top circle is labeled 'r'.

$$C = \frac{2\pi\epsilon}{\log\left(\frac{r_o}{r_i}\right)}$$

A diagram of a coaxial cable cross-section. It consists of a central yellow circle with radius 'r\_i' and an outer yellow ring with outer radius 'r\_o'.

$$C = \frac{w\epsilon}{s} + \frac{2\pi\epsilon}{\log(4s/r)}$$

A diagram of a rectangular plate capacitor. It shows two blue rectangular plates separated by a distance 's'. The top plate has a radius 'r' at its corners, and curved lines represent the fringing electric field. The formula below the diagram is  $C = \frac{w\epsilon}{s} + \frac{2\pi\epsilon}{\log(4s/r)}$ .

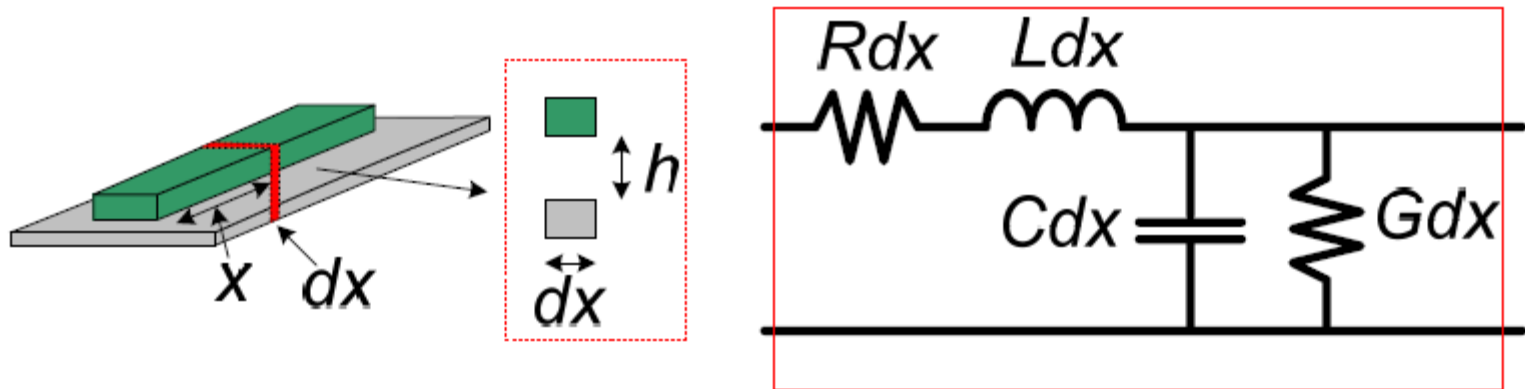
|| Plate + Fringing

- Inductance

$$L = \frac{\epsilon\mu}{C}$$



# Wires/Cables as Transmission Lines



- Electromagnetic field propagation
- Per unit length,
  - $R$ ,  $L$ , and  $C$  are the resistance, inductance, and capacitance of the conductor structure
  - $G$  represents loss in the dielectric between the conductors
- For a lossless transmission line,  $R = 0$  and  $G = 0$

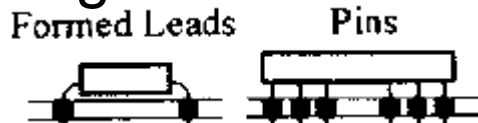




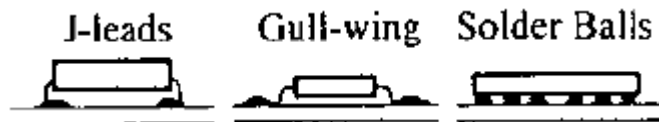
# IC Package Types

- Package needed to protect chips physically and thermally.
- Packaging pin count did not increase as on-chip aggregate bandwidth.
- Attachment to board

- Through-hole



- Surface-mount

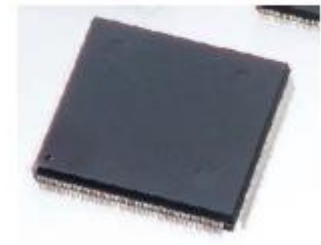


Package Type	Pin Count
Small Outline Package (SOP)	8 – 56
Quad Flat Package (QFP)	64 - 304
Plastic Ball Grid Array (PBGA)	256 - 420
Enhanced Ball Grid Array (EBGA)	352 - 896
Flip Chip Ball Grid Array (FC-BGA)	1089 - 2116

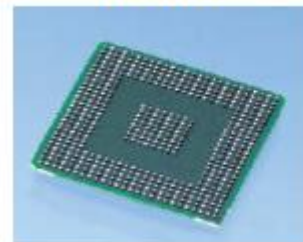
**SOP**



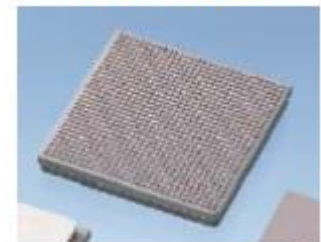
**QFP**



**PBGA**



**FC-BGA**



[Fujitsu]



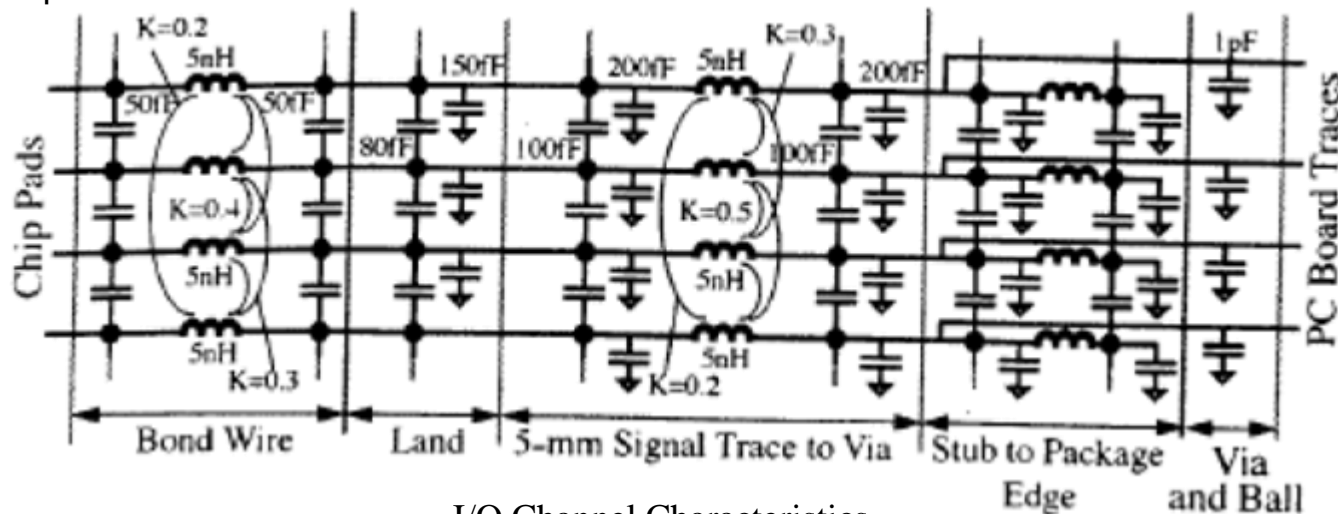
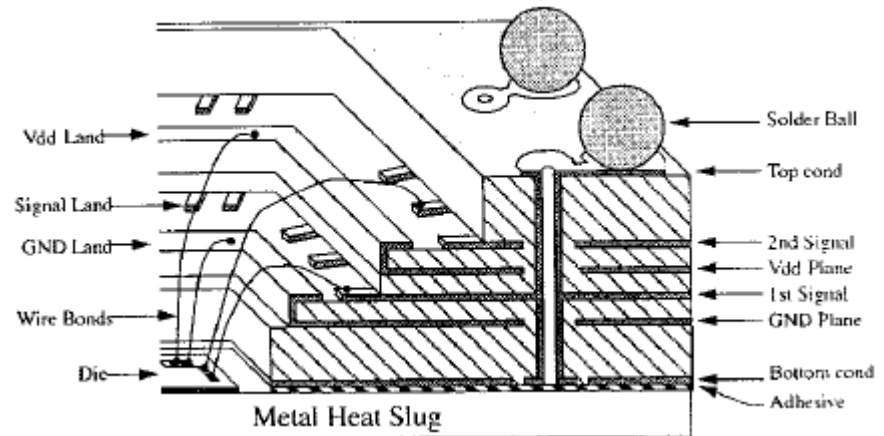
# IC Package Model

- **Bondwires**

- $L \sim 1 \text{ nH/mm}$
- Mutual inductance
- $C_{\text{couple}} \sim 20 \text{ fF/mm}$

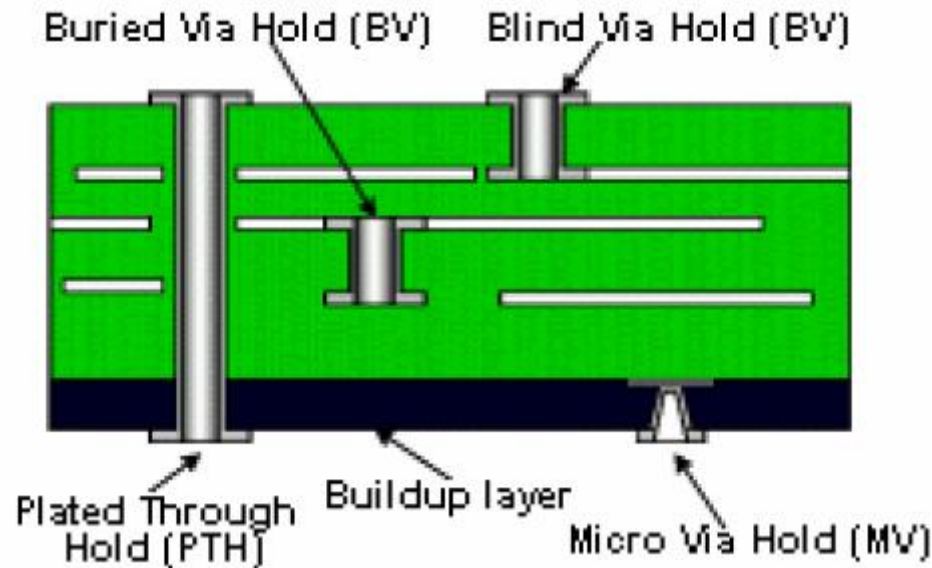
- **Package traces**

- $L \sim 0.7 - 1 \text{ nH/mm}$
- Mutual inductance
- $C_{\text{layer}} \sim 80 - 90 \text{ fF/mm}$
- $C_{\text{couple}} \sim 40 \text{ fF/mm}$



[Dally]

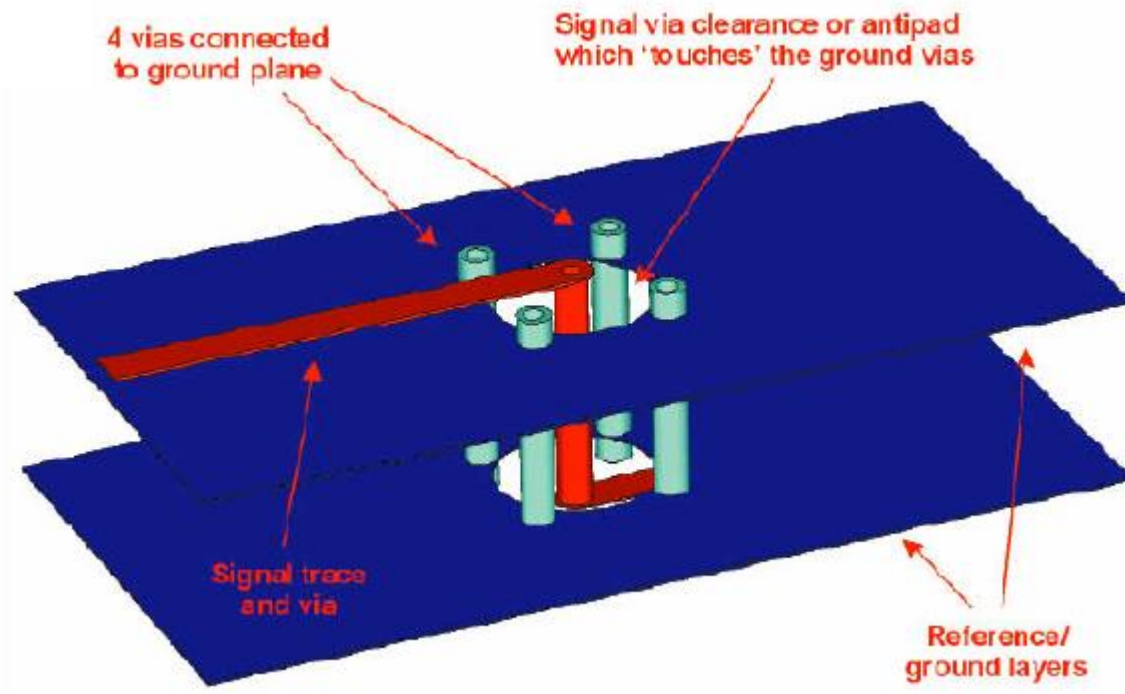
# PCB Vias



- **Made by drilling a hole through the board which is plated with copper**
  - Pads connect to signal layers/traces.
  - Clearance holes avoid power planes.
- **Blind vias are better than through vias with respect to signal integrity as they are better impedance-controlled.**



# Coaxial-Type Vias

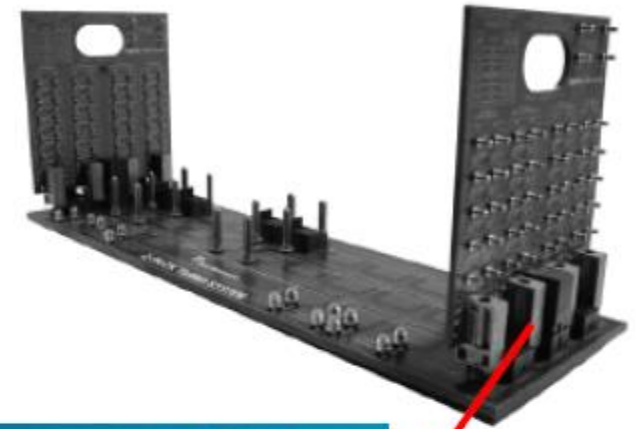
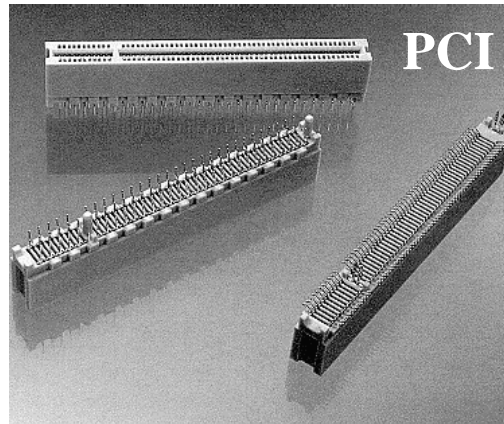
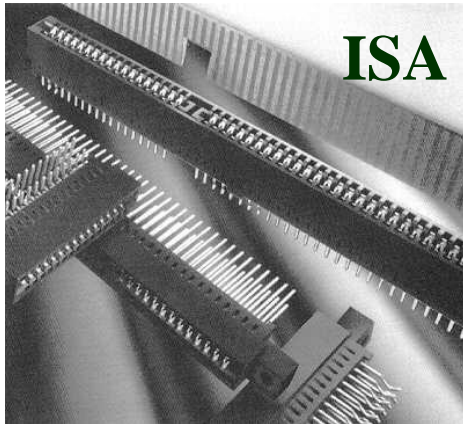


- Extra vias for ground connections
- Spacing used for impedance control



# Connectors

- Connectors are used to transfer signals from board to board.
- Typical differential pair density ranges between 16 – 32 pairs/10mm.





# Common Connectors

- Typical frequencies where attenuation gets to 1 dB.

Connector type	Frequency Range
N-type (Neil)	11-18GHz
APC (sexless)	<18GHz
SMA (2.4mm air-gap)	<26GHz (26-50GHz)
SMB (snap on)	<3GHz
BNC (baby Neil)	<500MHz
D-Connector (RJ connectors)	<100MHz
Ribbon	<20MHz



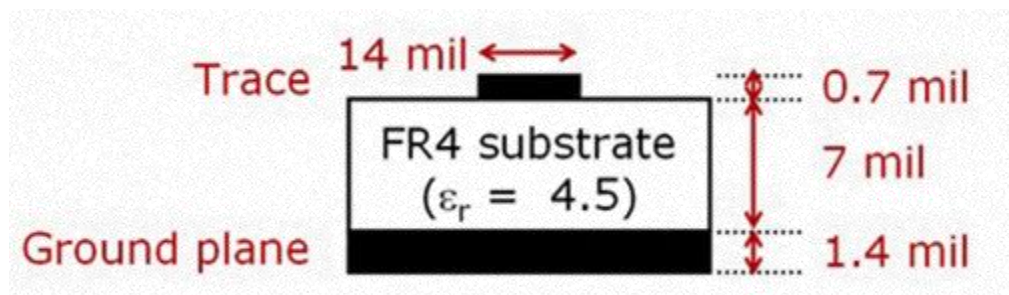
# Outline

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# Channel Characteristics

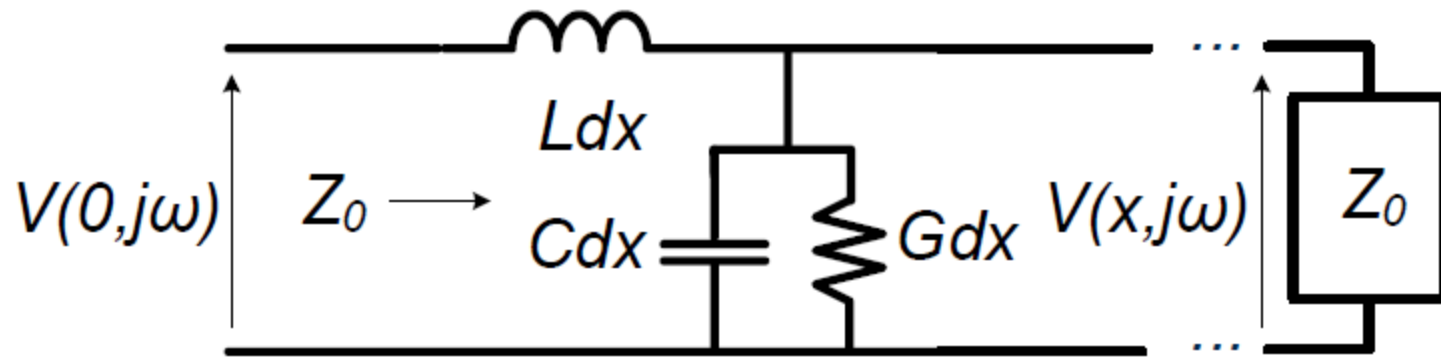


- Flight time typically exceeds bit period in Gb/s signaling
- Consider 5 Gb/s signaling over a 6'' PCB trace
  - Flight time is  $\sim 1$  ns. Bit period (1 UI) is 200 ps.
  - In any instant, five bits traveling on the channel.
- Channel cannot be considered lumped.
- Trace is modeled as transmission line.
- Effects include signal attenuation, reflection and cross-talk.





# Loss Mechanisms: Dielectric Loss (1)



- The parallel conductance causes signal attenuation.

$$\gamma(j\omega) = j\omega\sqrt{LC}\sqrt{1 - j\frac{G}{\omega C}} \approx +\underbrace{\frac{1}{2}\left(\frac{G}{\omega C}\right)}_{\tan\delta}\omega\sqrt{LC} + j\omega\sqrt{LC}$$

Loss tangent

- The loss increases with transmission wire length.

$$|H_D(x, j\omega)| \triangleq \left| \frac{V(x, j\omega)}{V(0, j\omega)} \right| = \left| e^{-\gamma(j\omega)x} \right| = e^{-\alpha(\omega)x} = e^{-\frac{1}{2}x\omega\sqrt{LC}\tan\delta}$$



# Loss Mechanisms: Dielectric Loss (2)

- **Loss tangent can be approximated as a constant**
  - Not true, but a reasonable approximation

$$\begin{aligned}\text{Dielectric loss} &= -20 \log_{10} |H_D(j2\pi f)| \\ &= (20\pi f \sqrt{LC} \tan \delta \log_{10} e) x \text{ dB} \\ &= \left( 20\pi f \frac{\sqrt{\epsilon_r}}{c} \tan \delta \log_{10} e \right) \text{ dB/meter}\end{aligned}$$

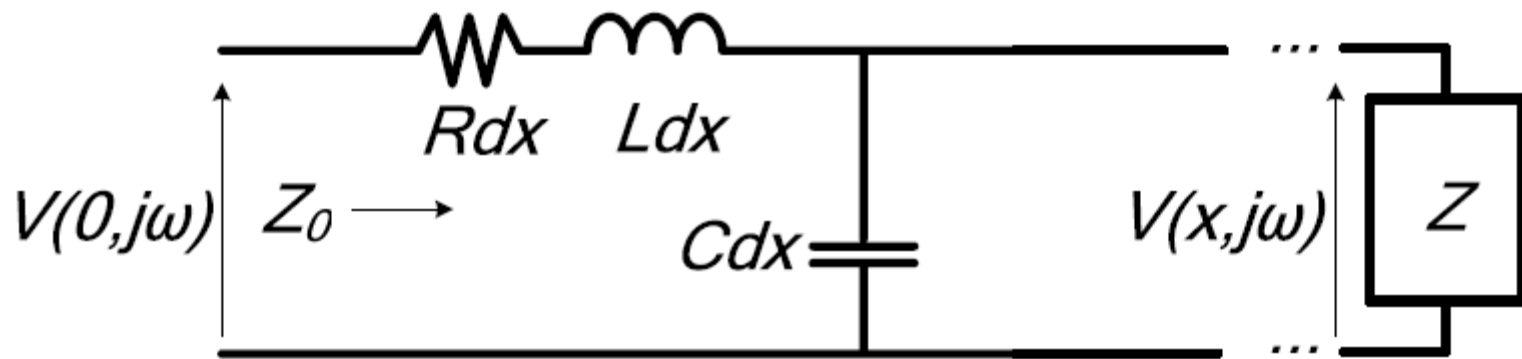
Material	$\tan \delta$
FR4	0.035
Polyimide	0.025
GETEK	0.010
Teflon	0.001

$$\text{Note: } \sqrt{LC} = \frac{\sqrt{\epsilon_r \mu_r}}{c}; \quad \mu_r = 1 \text{ usually}$$

- **Loss increases linearly with wire length.**
- **Loss rolls off as 20 dB/decade (like a 1<sup>st</sup> order filter past its bandwidth)**



# Loss Mechanisms: Conductive Loss (1)



- Finite conductivity of the conductors causes loss.

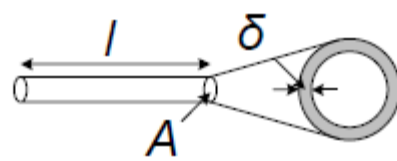
$$\gamma(j\omega) = j\omega\sqrt{LC} \sqrt{1 - j\frac{R}{\omega L}} \approx +\frac{1}{2}\frac{R}{Z_0} + j\omega\sqrt{LC}$$

- Again, loss increases with transmission wire length.

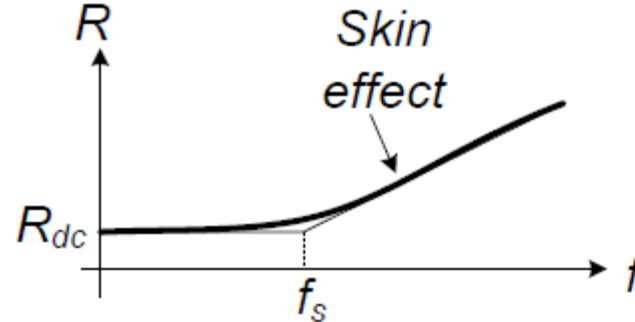
$$|H_C(x, j\omega)| = e^{-\alpha(\omega)x} = e^{-\frac{1}{2}\frac{R}{Z_0}x}$$



# Loss Mechanisms: Conductive Loss (2)



$$\delta = \frac{1}{\sqrt{\pi f \mu \sigma}}$$

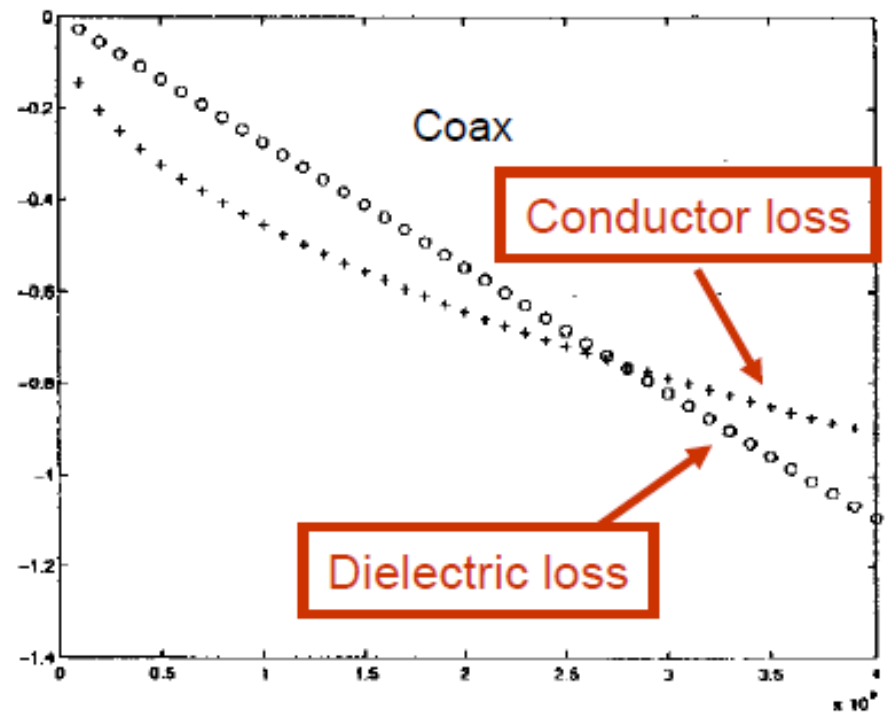
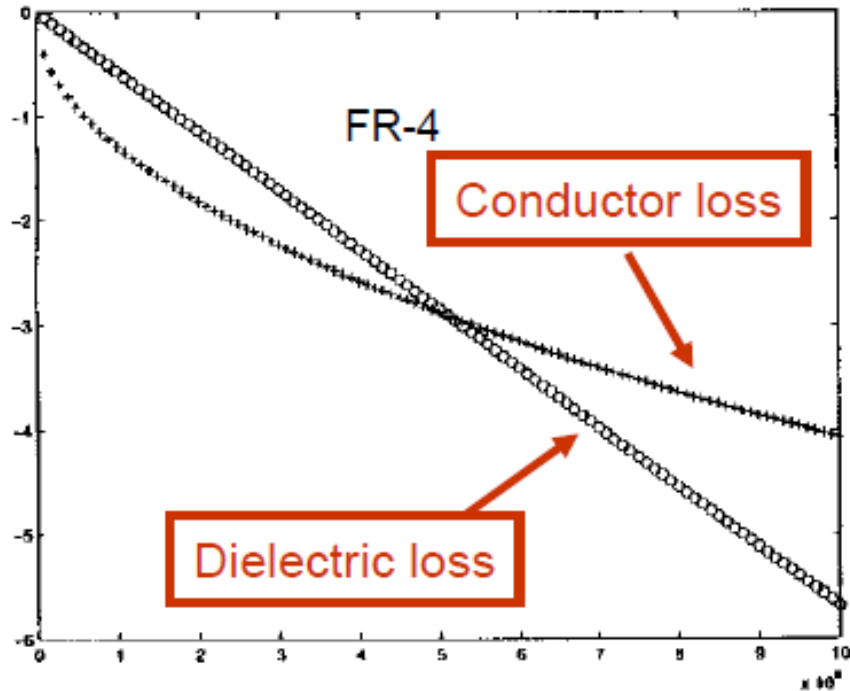


- **Conductivity decreases at high frequencies.**
  - Called skin effect.
  - Current flows close to the surface in a thin layer.
  - Skin depth,  $\delta$ , is the depth where the current has fallen to  $e^{-1}$ .
  - $f_s$  is the frequency where  $\delta$  is equal to  $r$  or  $h/2$ .

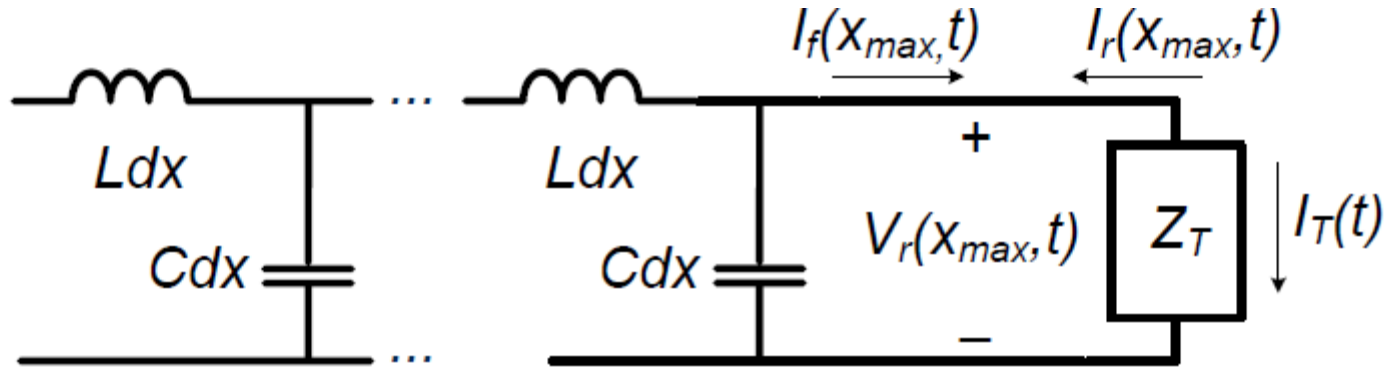
$$\text{DC resistive loss} = 10 \frac{R_{dc}}{Z_0} \log_{10} e \text{ dB/meter}$$

$$\text{Skin effect loss} = 10 \frac{R_{dc}}{Z_0} \left( \frac{f}{f_s} \right)^{1/2} \log_{10} e \text{ dB/meter}$$

# Losses: Cable vs. PCB Trace



# Reflection



- Suppose T-line is terminated by  $Z_T \neq Z_0$ .
- Forward wave will launch a backward traveling wave.
  - Backward wave starts at  $Z_T$  with the following time waveform

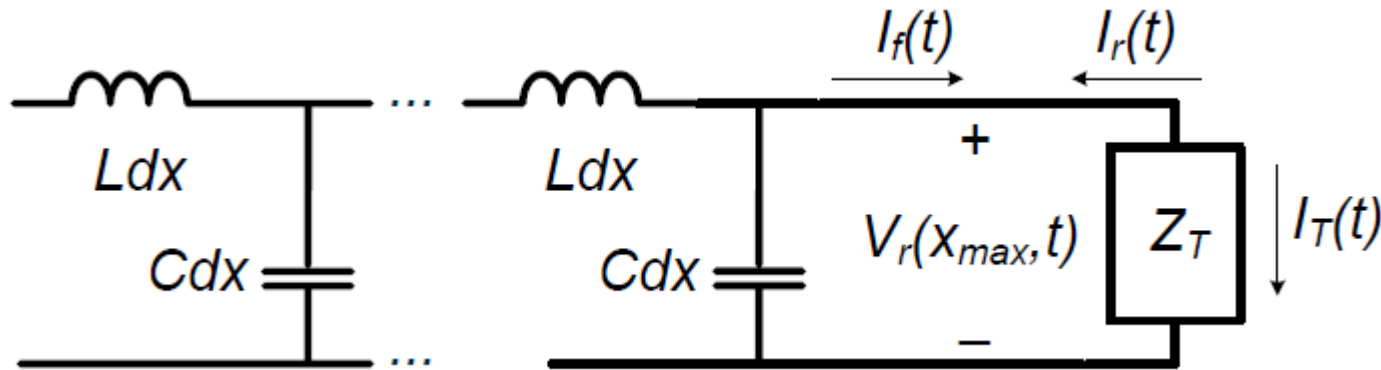
$$V_r(x_{\max}, t) = \Gamma V_f(x_{\max}, t), \text{ where } \Gamma = \frac{Z_T - Z_0}{Z_T + Z_0}$$

- The reflected current is also given by the reflection coefficient,  $\Gamma$ 

$$I_r(x_{\max}, t) = \Gamma I_f(x_{\max}, t)$$



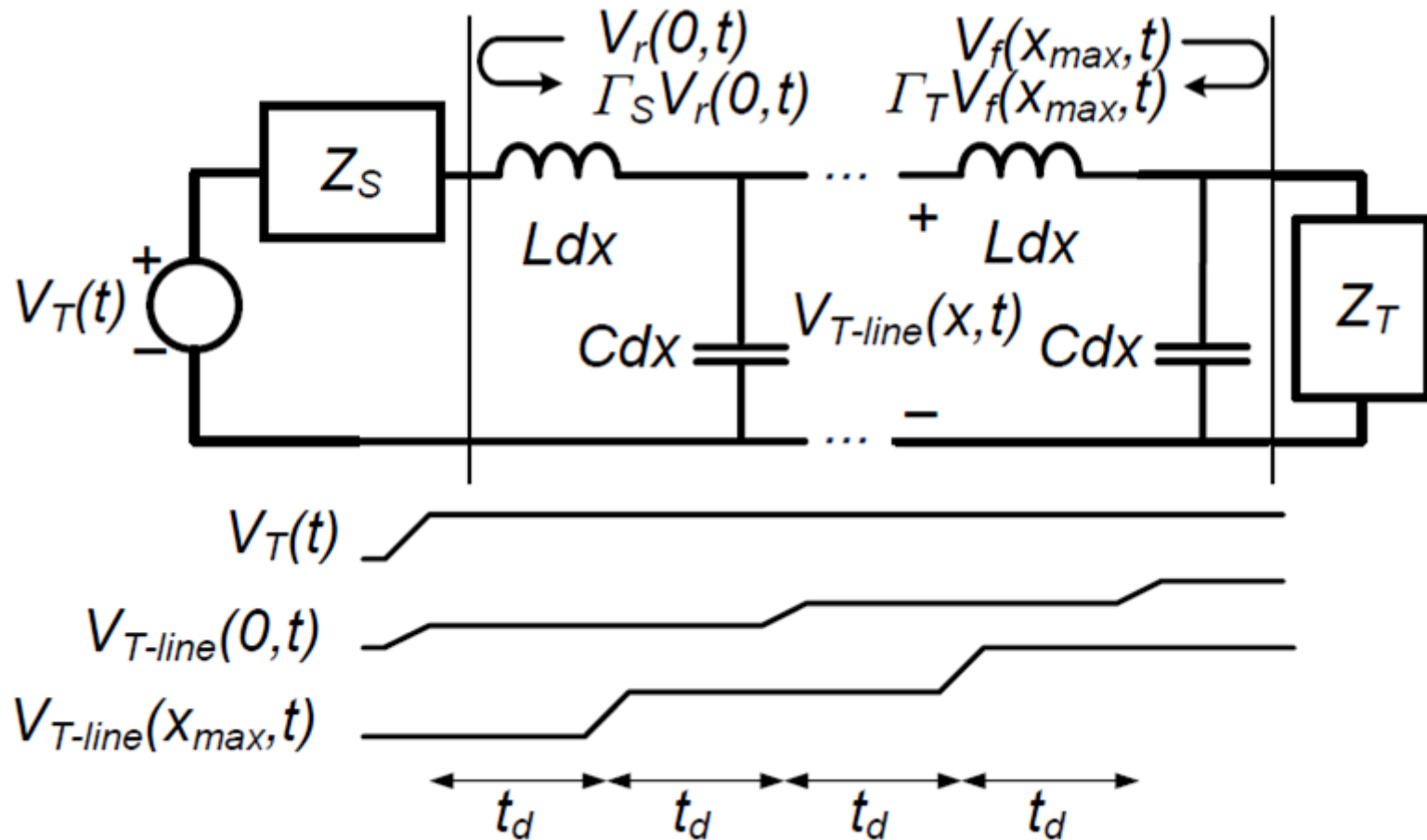
# Termination Examples



- The voltage drop at  $Z_T$  is  $V_{T-line}(x_{max}, t) = V_f(x_{max}, t) + V_r(x_{max}, t)$
- If  $Z_T = Z_0$ ,  $V_r(x_{max}, t) = 0$ 
  - $V_{T-line}(x_{max}, t) = V_f(x_{max}, t) + V_r(x_{max}, t) = V_f(x_{max}, t)$
  - Like an infinitely-long TL
- If  $Z_T = 0$ ,  $V_r(x_{max}, t) = -1 * V_f(x_{max}, t)$ 
  - $V_{T-line}(x_{max}, t) = V_f(x_{max}, t) + V_r(x_{max}, t) = 0$
- If  $Z_T = \infty$ ,  $V_r(x_{max}, t) = V_f(x_{max}, t)$ 
  - $V_{T-line}(x_{max}, t) = V_f(x_{max}, t) + V_r(x_{max}, t) = 2 * V_f(x_{max}, t)$



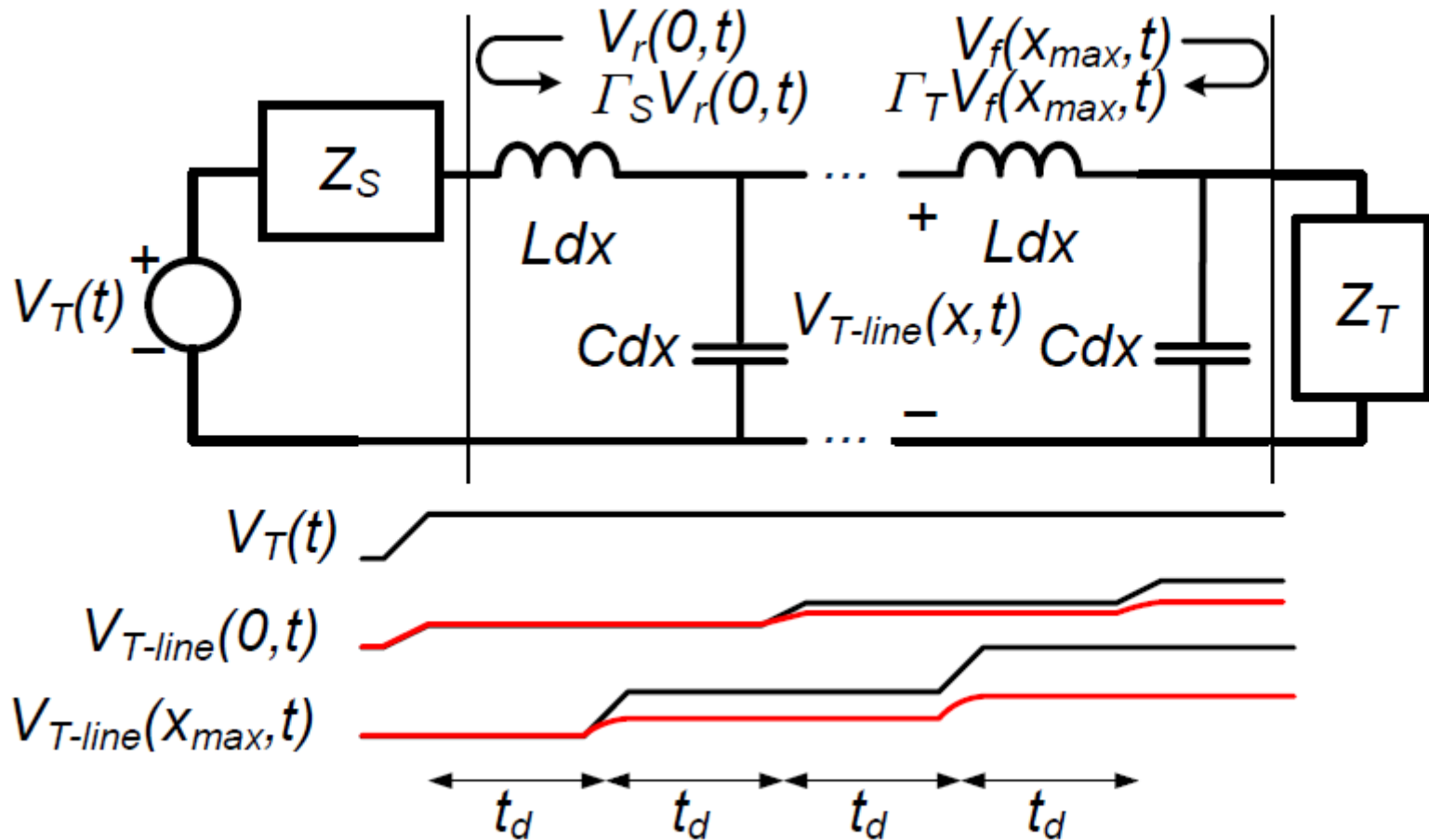
# TL Wave Reflections



- Multiple reflections are caused by the forward and backward waves reflecting at the source and load boundaries.



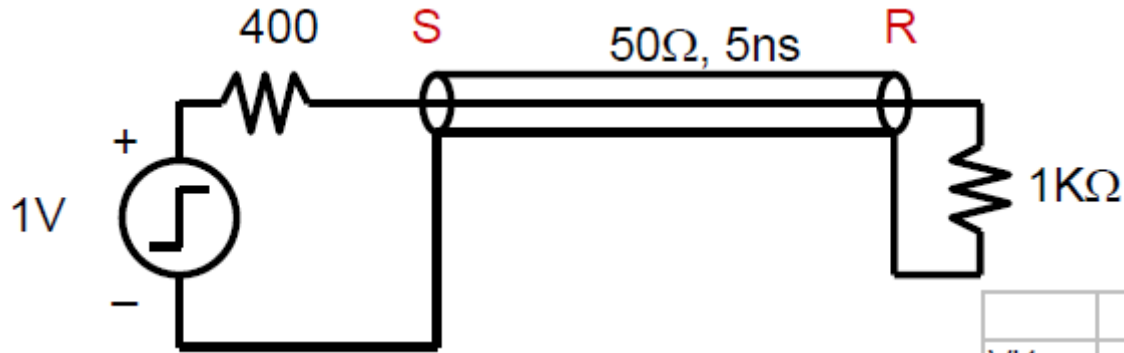
# Lossy TL Wave Reflections



- Loss in TLs reduce the effects of reflections significantly



# Numerical Example of TL Reflections

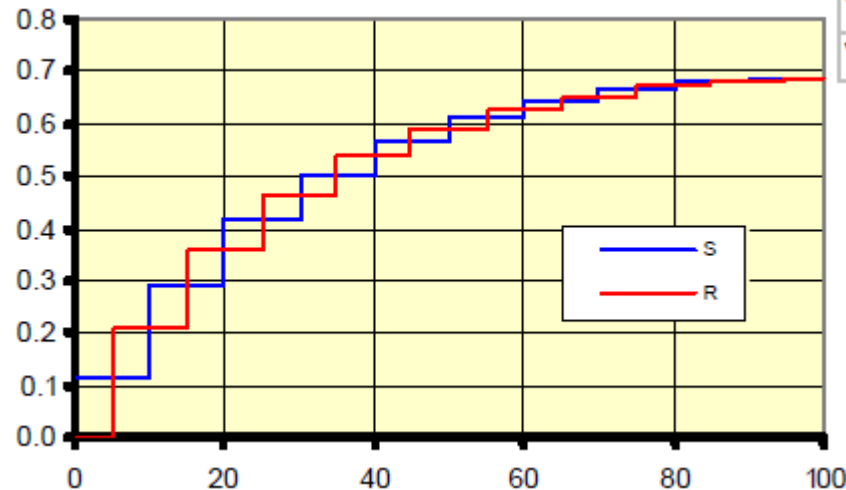


$$V_i = 1V \left( \frac{50}{400 + 50} \right) = 0.111V$$

$$k_{rS} = \frac{400 - 50}{400 + 50} = 0.778$$

$$k_{rR} = \frac{1000 - 50}{1000 + 50} = 0.905$$

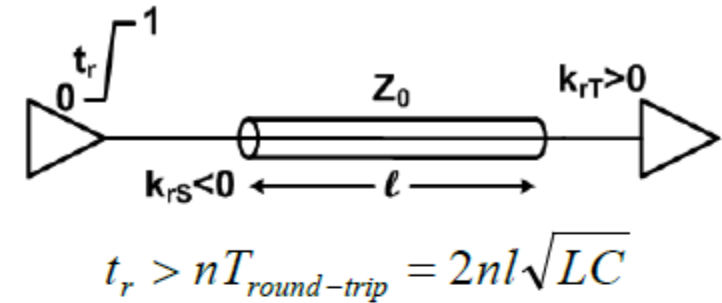
	Vwave	Vline	t
Vi1	0.111	0.111	0
Vr1	0.101	0.212	5
Vi2	0.078	0.290	10
Vr2	0.071	0.361	15
Vi3	0.055	0.416	20
Vr3	0.050	0.465	25
Vi4	0.039	0.504	30
Vr4	0.035	0.539	35
Vi5	0.027	0.566	40



# Termination Schemes (1)

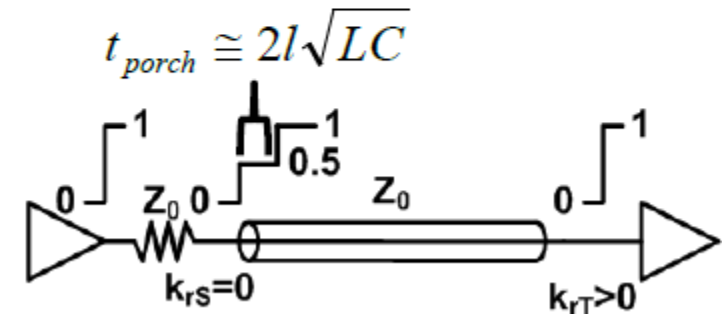
- **No Termination**

- Little to absorb line energy
- Can generate oscillating waveform
- Line must be very short relative to signal transition time ( $n = 4 - 6$ )
- Limited off-chip use



- **Source Termination**

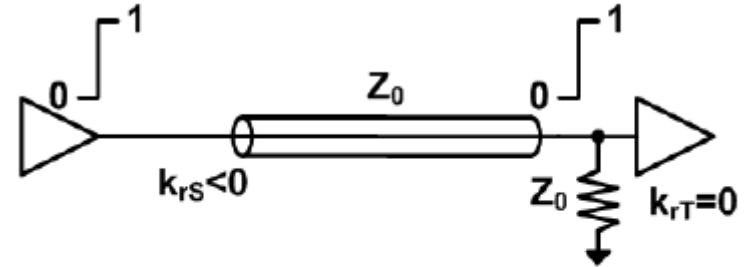
- Source output takes 2 steps up
- Used in moderate speed point-to-point connections



# Termination Schemes (2)

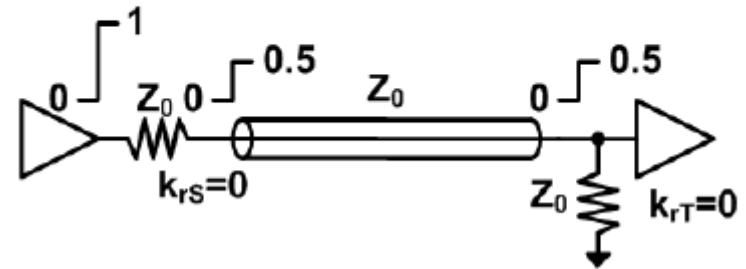
- **Receiver Termination**

- No reflection from receiver
- Watch out for intermediate impedance discontinuities
- Little to absorb reflections at driver



- **Double Termination**

- Best configuration for minimum reflections
- Get half the swing relative to single termination
- Most common termination scheme for high performance serial links



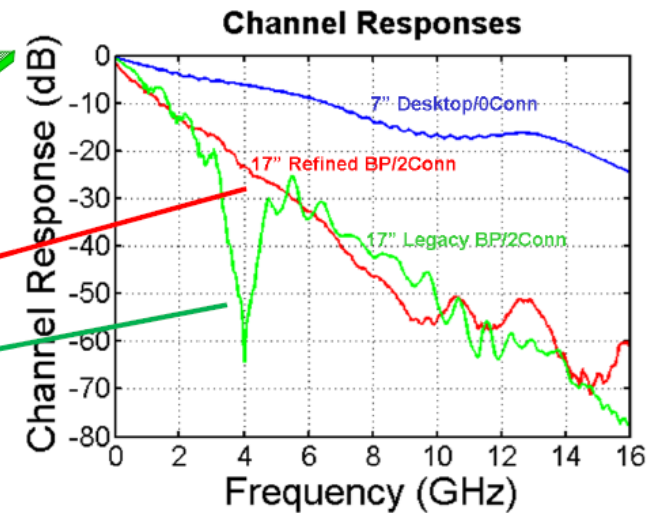
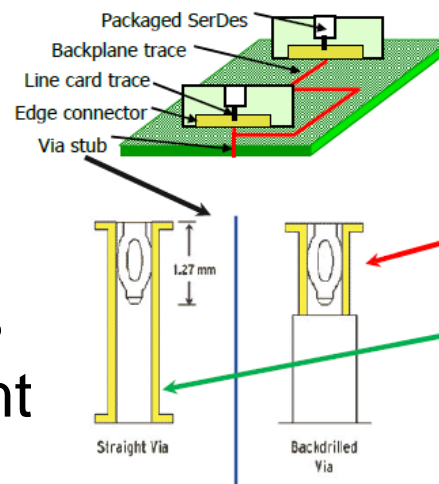
# Sources of Reflections

- **Z-Discontinuities**

- PCB Z mismatch
- Connector Z mismatch
- Vias Z mismatch
- Device parasitics

- **Example Via Stubs**

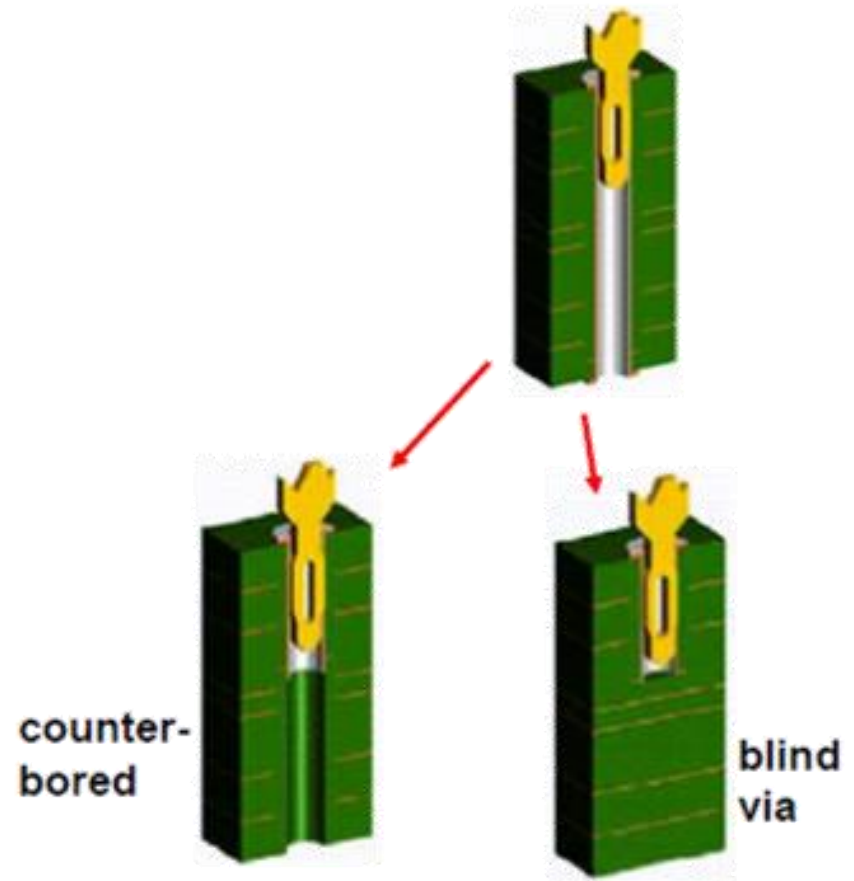
- Legacy backplanes have default straight vias
- Refined backplanes have expensive backdrilled vias



# Minimizing Via Stubs

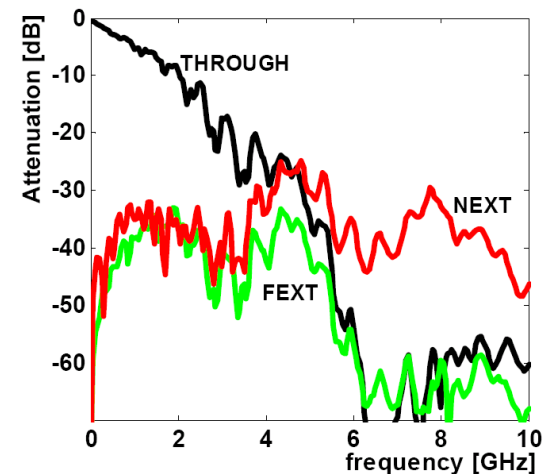
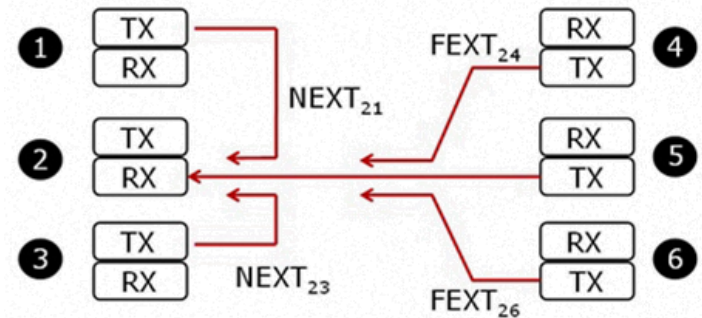
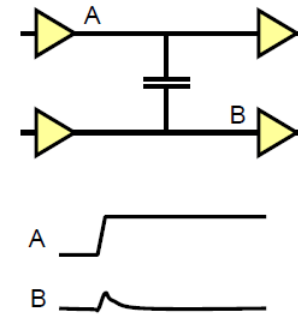
- Thinner PCBs
- Better vias
- But are expensive solutions

Layer 1	0.5 Oz
Layer 2	10 mil
Layer 3	10 mil
Layer 4	10 mil
Layer 5	10 mil
Layer 6	10 mil
Layer 7	10 mil
Layer 8	10 mil
Layer 9	10 mil
Layer 10	10 mil
Layer 11	10 mil
Layer 12	10 mil

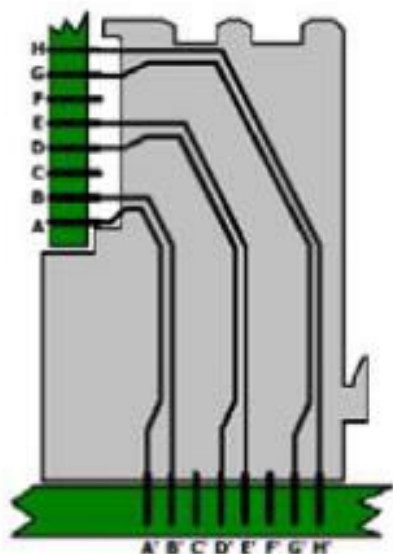


# Cross-Talk

- Noise induced by one signal that interferes with another signal
- Capacitive coupling between on-chip lines
- Capacitive and inductive coupling between off-chip lines
- Coupling over shared signal returns
- Near end cross-talk (NEXT) and far end cross-talk (FEXT)
- Disturbances on both voltage and current
- Can exceed signal at high frequencies.



# Connectors and Cross-Talk



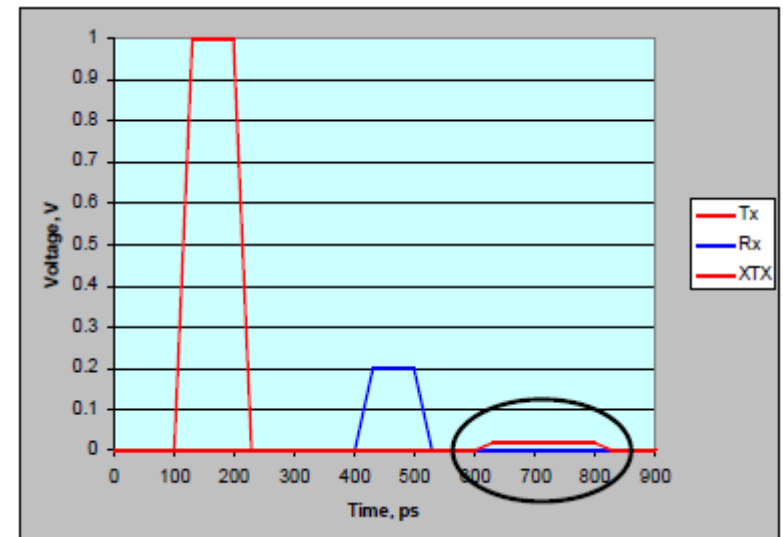
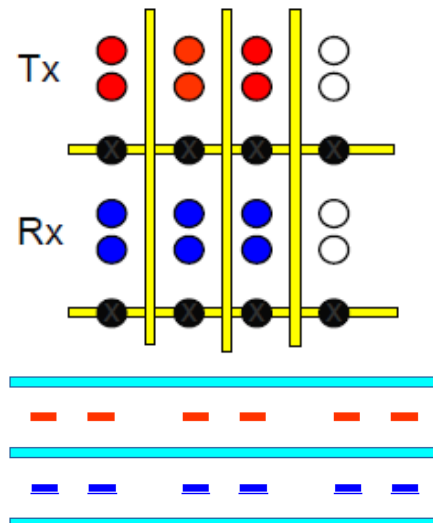
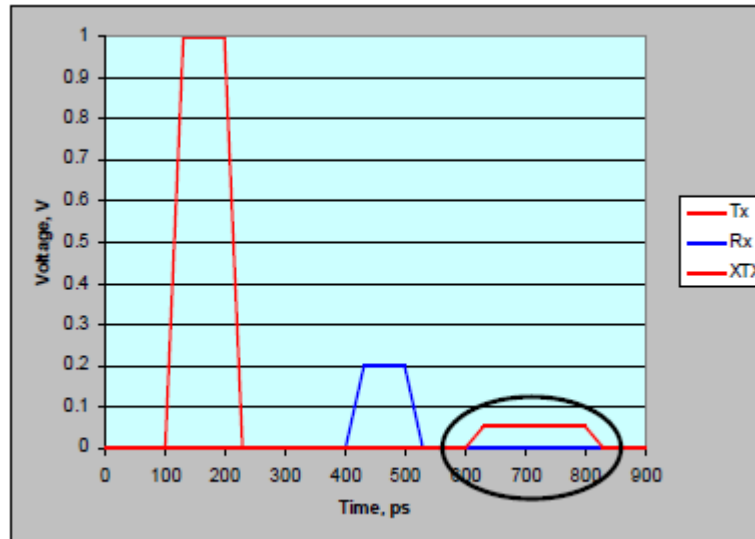
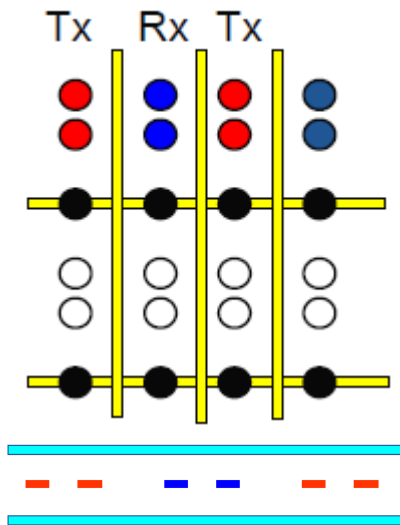
<u>HSD 8 Propagation Delay</u> Calculated from length		
H → H'		200ps
G → G'		194ps
E → E'		151ps
D → D'		145ps
B → B'		108ps
A → A'		99ps

	NEXT	FEXT
	55 ps (20-80%)	55 ps (20-80%)
	80ps (10-90%)	80ps (10-90%)
AB	4.4%	3.7%
DF	3.3%	2.6%
GH	3.3%	2.6%
JK	4.3%	3.5%

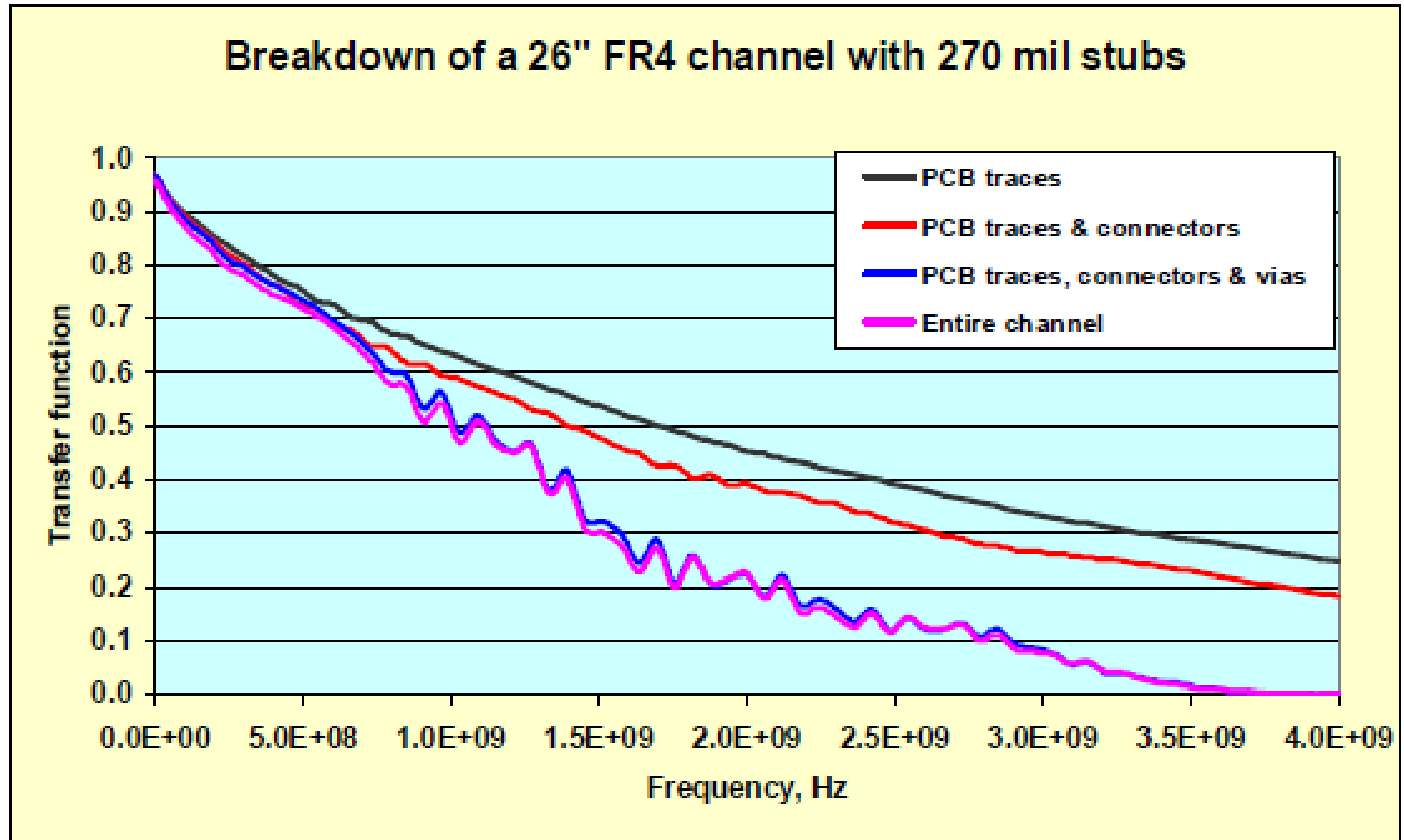
- Connectors have tight footprint constraints.
- Hard to match pairs.
- Big source of impedance discontinuities.
- But above all, a major source of cross-talk.



# NEXT: To Do and Not To Do



# Everything together



# Outline

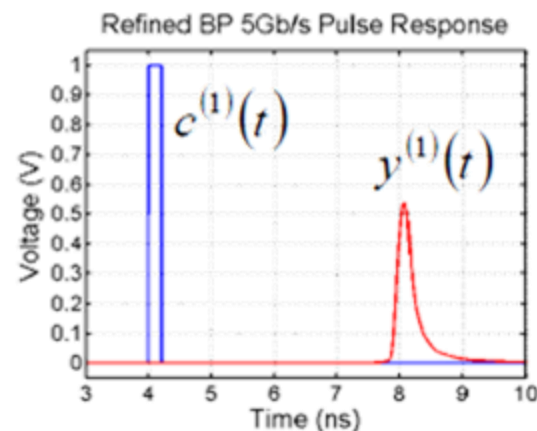
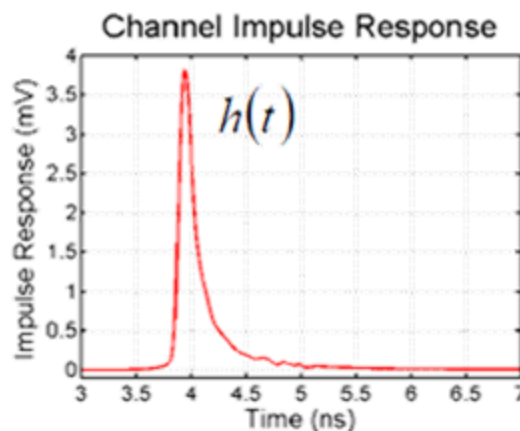
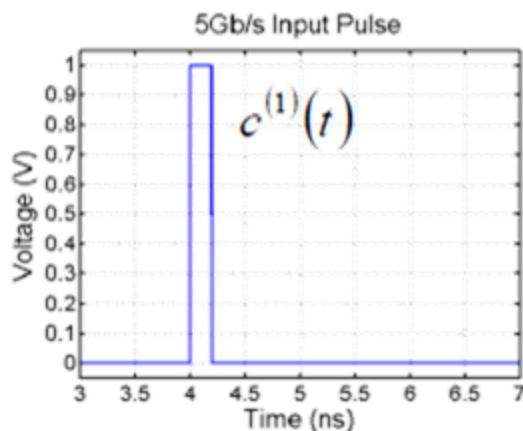
---

- **Channel Components**
  - Wires (PCB traces, Co-axial cables, twisted pairs, ..etc.)
  - IC Packages
  - Vias
  - Connectors
- **Channel Impairments**
  - Limited Bandwidth - Loss
  - Reflections
  - Cross-Talk
- **Channel Representations**
  - Impulse Response
  - S-Parameters
  - Eye Diagram
  - Time-Domain Reflectometry (TDR)

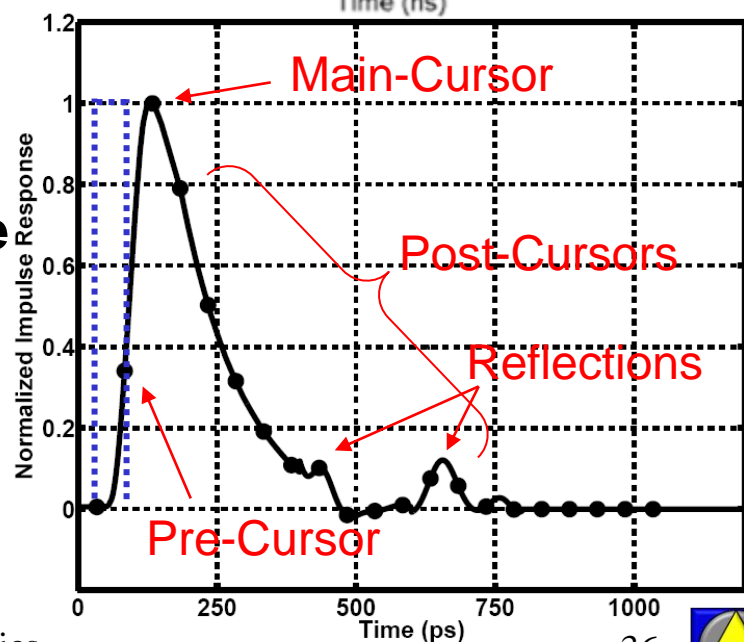


# Channel Pulse Response

$$y^{(1)}(t) = c^{(1)}(t) * h(t)$$

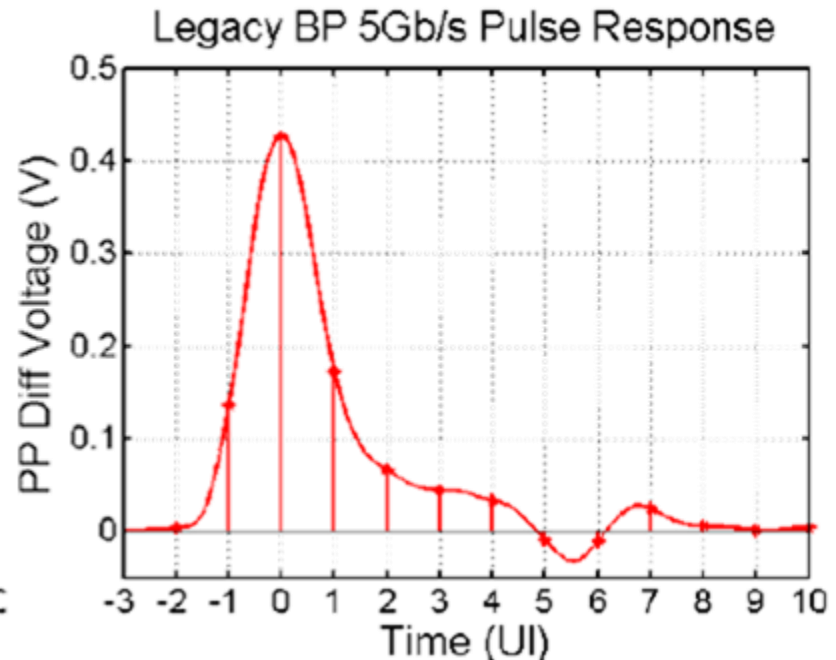
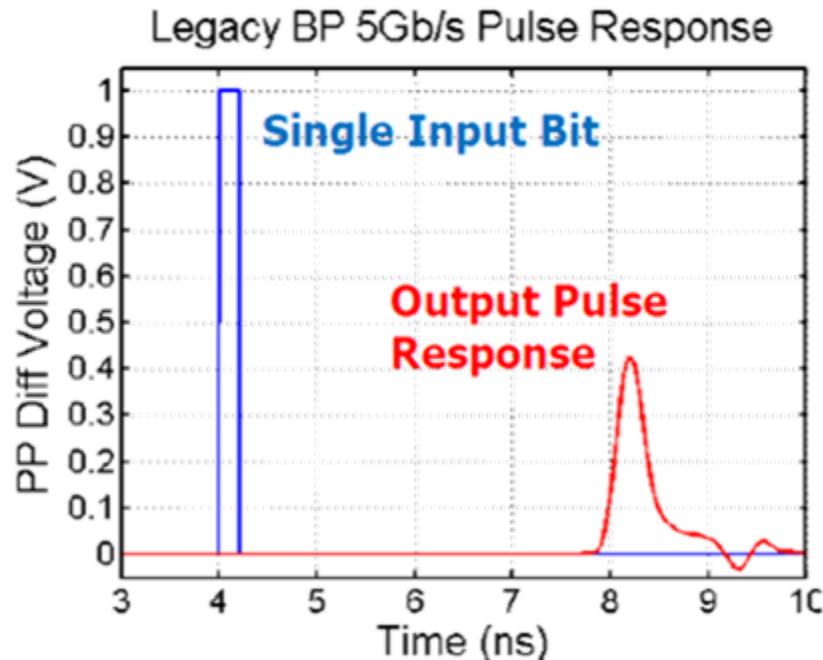


- TX pulse spreads in time as it travels through the channel.
- Channel's pulse response is used in time domain simulations and link analysis.
- Many post-cursors and few pre-cursors exist due to spreading.
- Spreading causes interference with adjacent symbols (ISI).



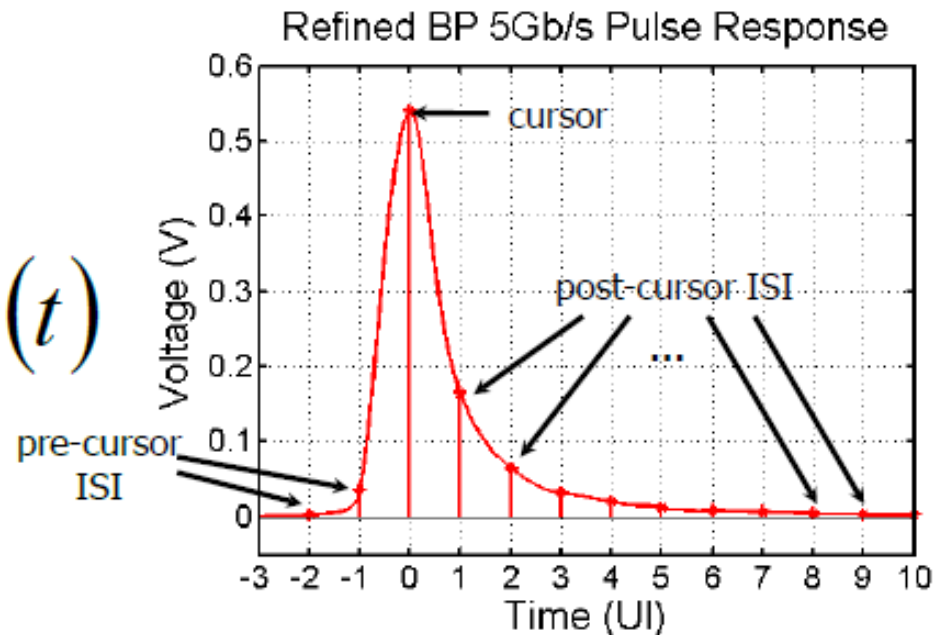
# Inter-Symbol Interference (ISI)

- ISI is caused by channel loss (dispersion) and reflections.
- Previous bits residual state can distort the current bit.
- ISI creates a deterministic jitter in received signal's zero crossings.
- Left uncompensated, ISI leads to increased BER.



# Numerical Example

$$y^{(d_k)}(t) = c^{(d_k)}(t) * h(t)$$



$y^{(1)}(t)$  sampled relative to pulse peak:

[... 0.003 0.036 0.540 0.165 0.065 0.033 0.020 0.012 0.009 ...]

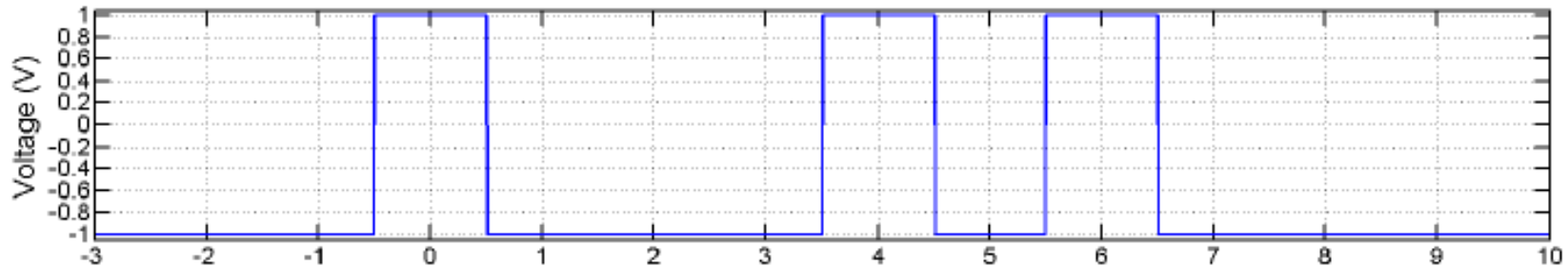
$k = [ \dots -2 \quad 1 \quad 0 \quad 1 \quad 2 \quad 3 \quad 4 \quad 5 \quad 6 \quad \dots ]$

By Linearity:  $y^{(0)}(t) = -1 * y^{(1)}(t)$

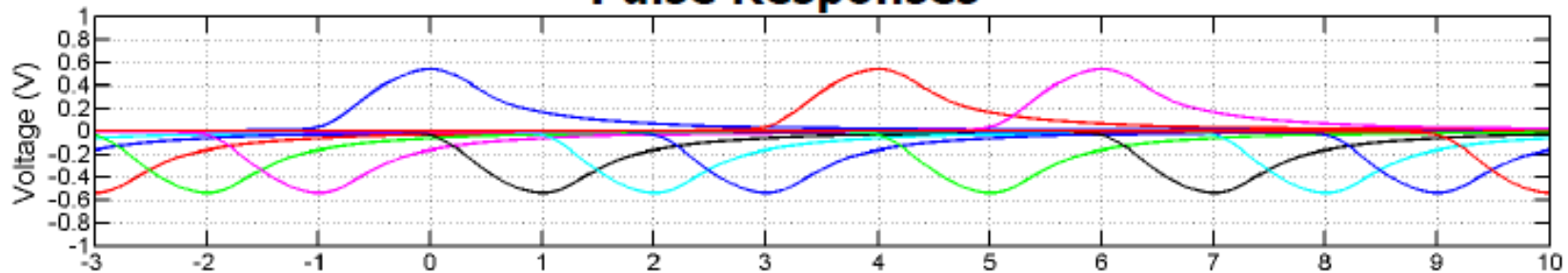


# Channel Data Stream Response

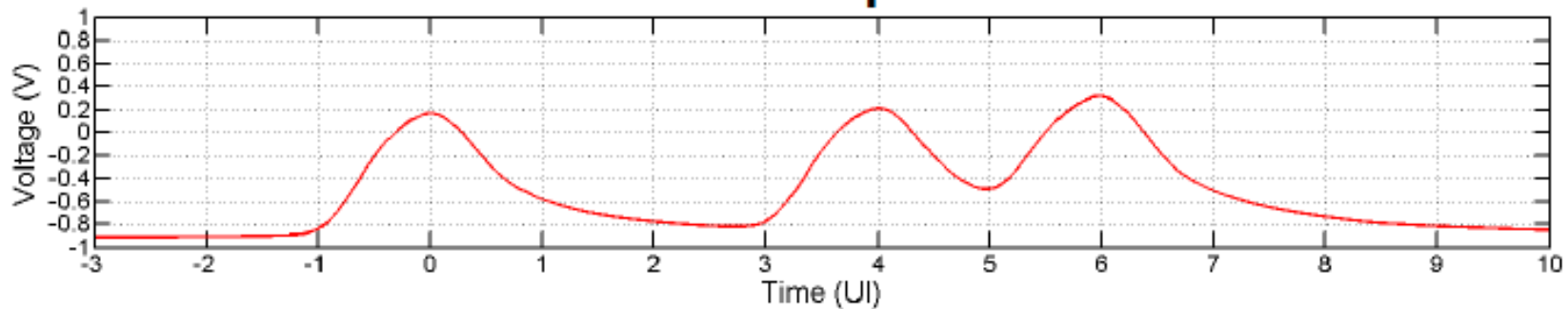
## Input Data Stream



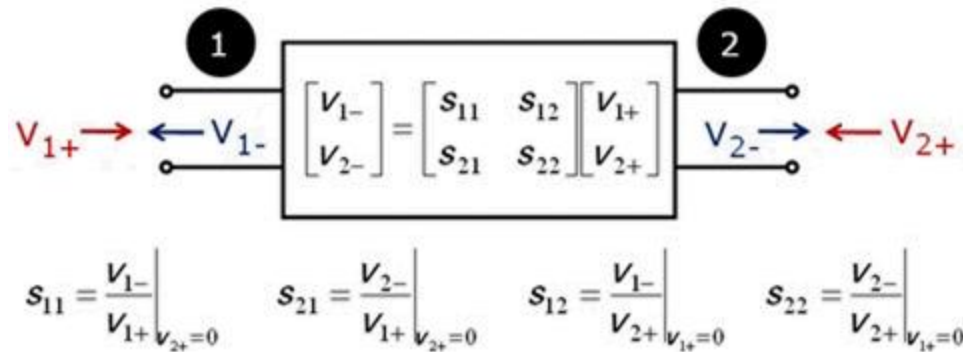
## Pulse Responses



## Channel Response



# Channel S-Parameters

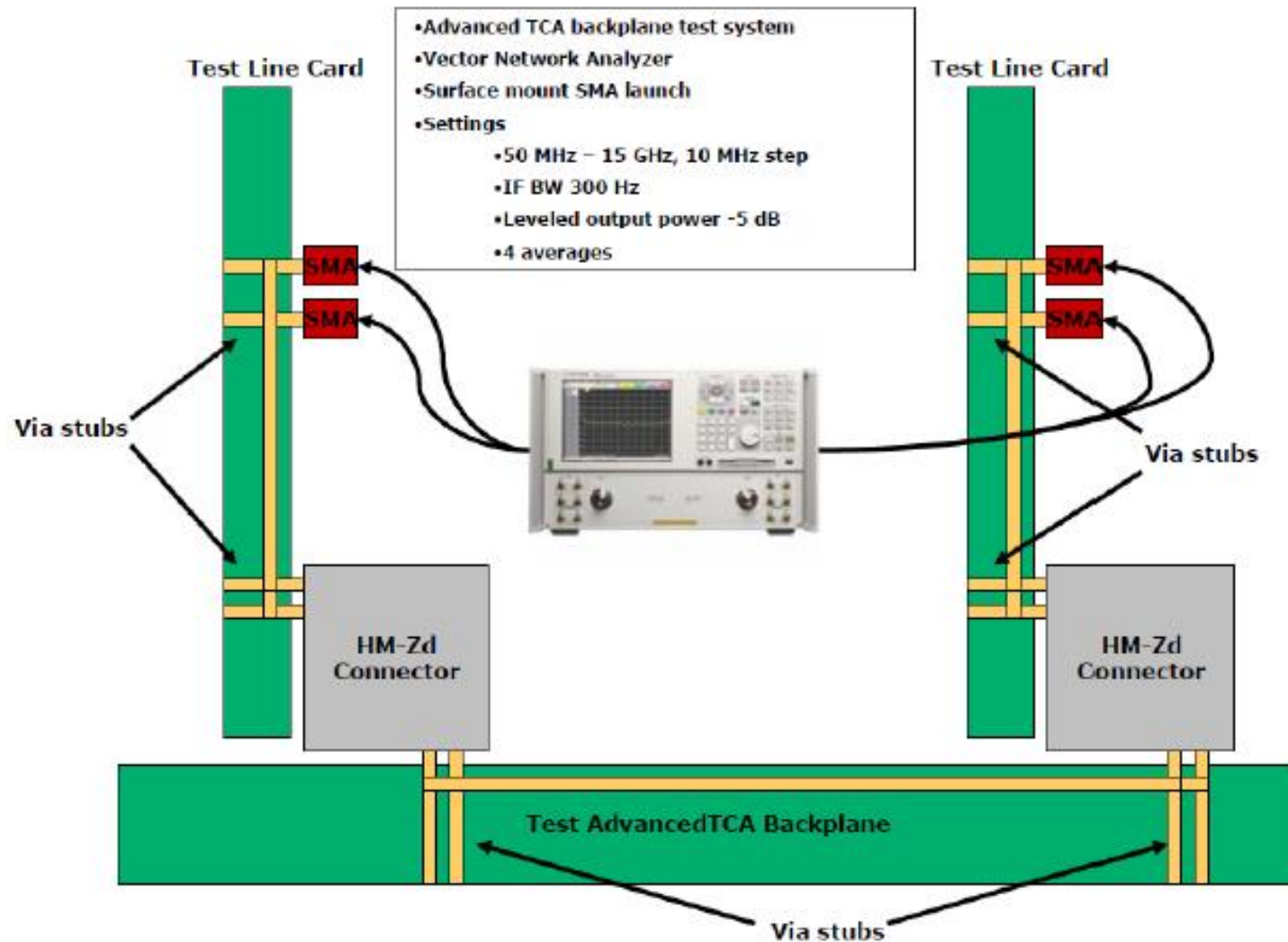


- **S-Parameters are easy to measure.**
  - Y, Z parameters need open and short conditions.
  - S-parameters are obtained with nominal termination.
- **$S_{11}$  measures reflection from channel, port 2 matched.**
- **$S_{11}$  is known as return loss.**
- **$S_{21}$  measures fraction of signal delivered to matched load.**
- **$S_{21}$  is known as insertion loss.**



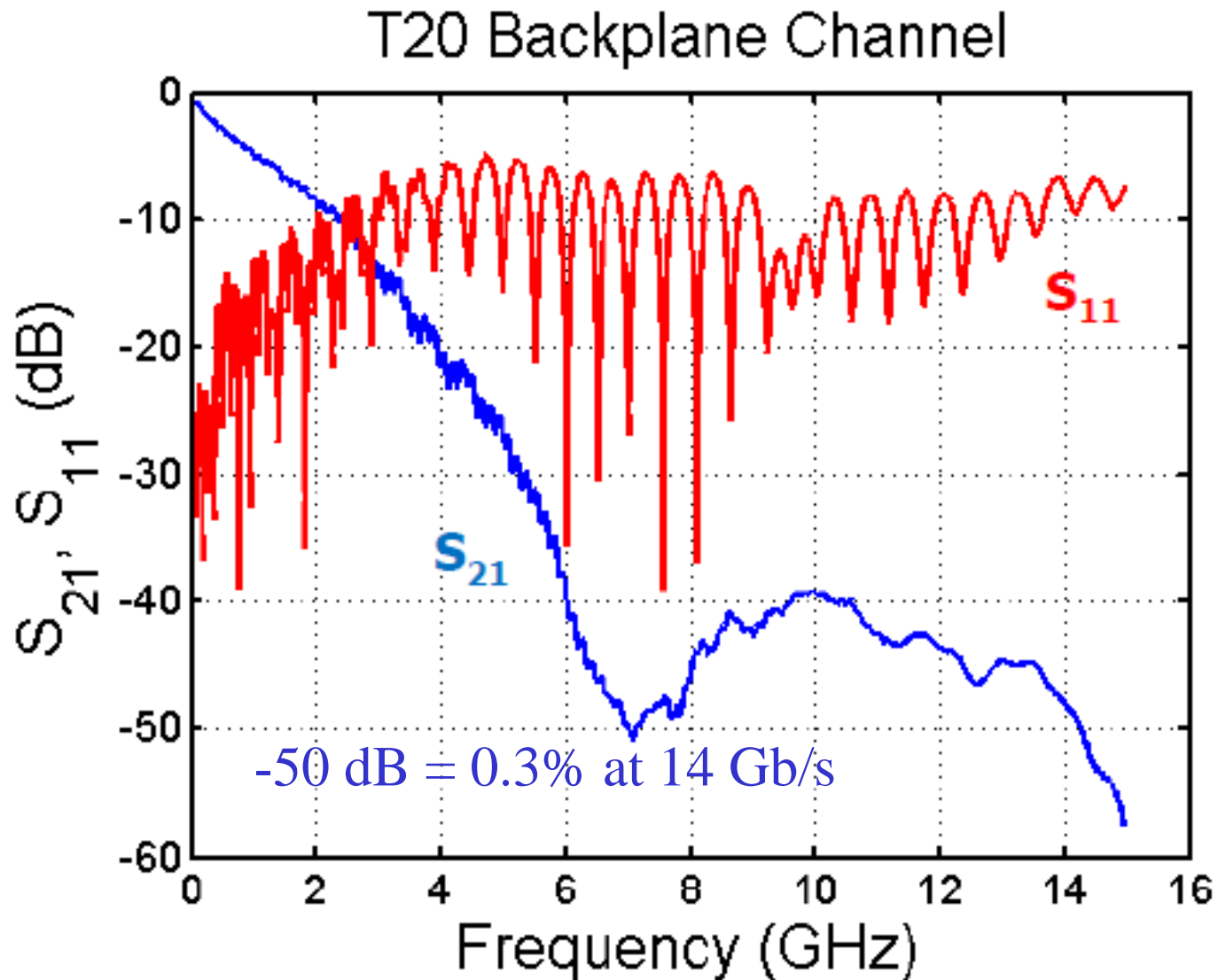


# S-Parameter Channel Example (1)



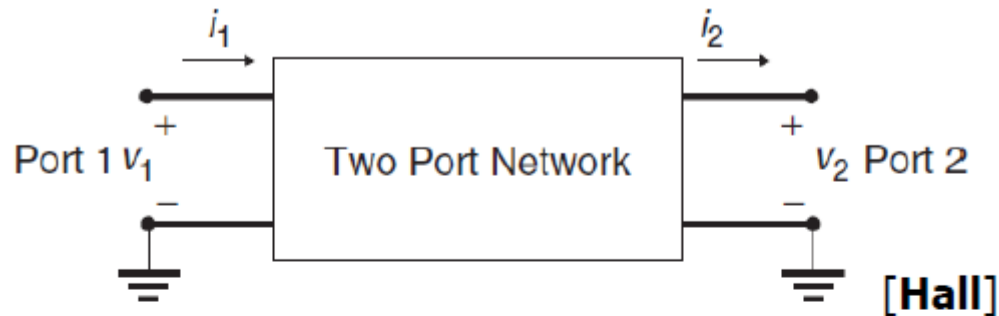
[Peters, IEEE Backplane Ethernet Task Force]

# S-Parameter Channel Example (2)



# Cascading S-Parameters

- Convert to ABCD matrix and cascade.



$$A = \left. \frac{v_1}{v_2} \right|_{i_2=0} \quad B = \left. \frac{v_1}{i_2} \right|_{v_2=0} \quad C = \left. \frac{i_1}{v_2} \right|_{i_2=0} \quad D = \left. \frac{i_1}{i_2} \right|_{v_2=0}$$

$$\begin{bmatrix} v_1 \\ i_1 \end{bmatrix} = \begin{bmatrix} A & B \\ C & D \end{bmatrix} \cdot \begin{bmatrix} v_2 \\ i_2 \end{bmatrix}$$

# Converting Between S & ABCD Parameters

**TABLE 9-3. Relationships Between Two-Port  $S$  and  $ABCD$  Parameters<sup>a</sup>**

$$\begin{bmatrix} S_{11} & S_{12} \\ S_{21} & S_{22} \end{bmatrix} \quad \begin{bmatrix} \frac{B - Z_n(D - A + CZ_n)}{B + Z_n(D + A + CZ_n)} & \frac{2Z_n(AD - BC)}{B + Z_n(D + A + CZ_n)} \\ \frac{2Z_n}{B + Z_n(D + A + CZ_n)} & \frac{B - Z_n(A - D + CZ_n)}{B + Z_n(D + A + CZ_n)} \end{bmatrix}$$

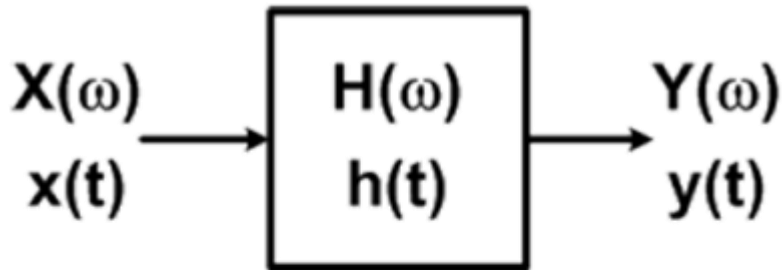
$$\begin{bmatrix} A & B \\ C & D \end{bmatrix} \quad \begin{bmatrix} \frac{(1 + S_{11})(1 - S_{22}) + S_{12}S_{21}}{2S_{21}} & Z_n \frac{(1 + S_{11})(1 + S_{22}) - S_{12}S_{21}}{2S_{21}} \\ \frac{1}{Z_n} \frac{(1 - S_{11})(1 - S_{22}) - S_{12}S_{21}}{2S_{21}} & \frac{(1 - S_{11})(1 + S_{22}) + S_{12}S_{21}}{2S_{21}} \end{bmatrix}$$

<sup>a</sup> $Z_n$  is the termination impedance at the ports.

[Hall]



# Impulse Response and S-Parameters (1)



$$Y(\omega) = H(\omega)X(\omega)$$

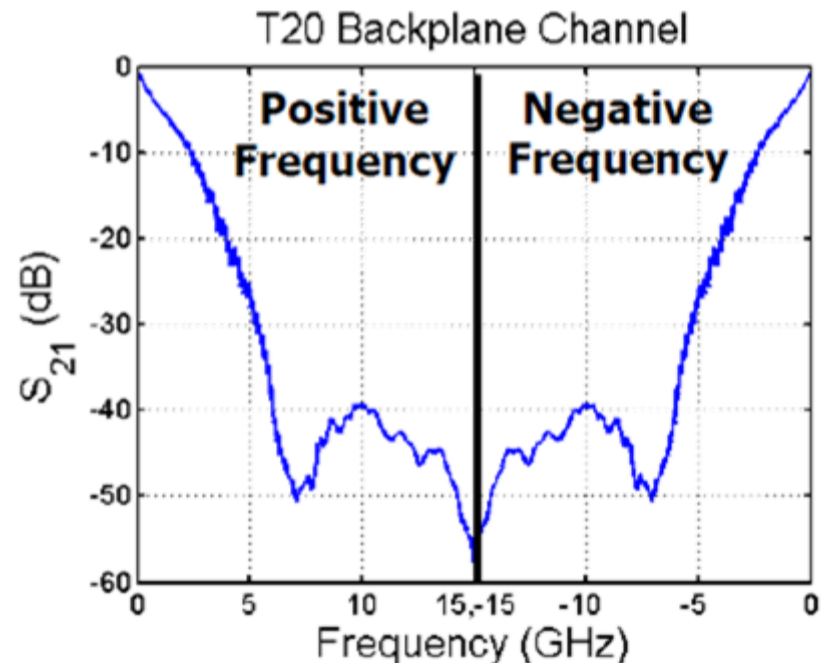
$$y(t) = h(t) * x(t) = \int_{-\infty}^{\infty} h(t - \tau)x(\tau) d\tau$$

$$h(t) = F^{-1}\{H(\omega)\}$$

- **Step 1: For ifft, produce negative frequency values and append to s-parameter data in the following manner**

$$S(-f) = S(f)^*$$

$$h(t) = F^{-1}\{S(\omega)\}$$



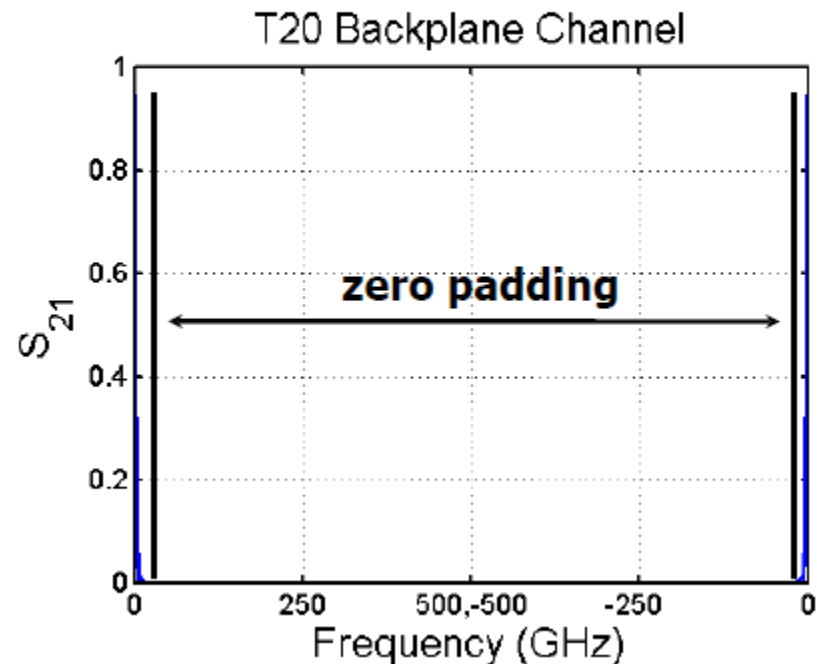
# Impulse Response and S-Parameters (2)

- Can perform ifft now, but will get an impulse response with time resolution of

$$\frac{1}{2f_{\max}} = \frac{1}{2(15\text{GHz})} = 33.3\text{ps}$$

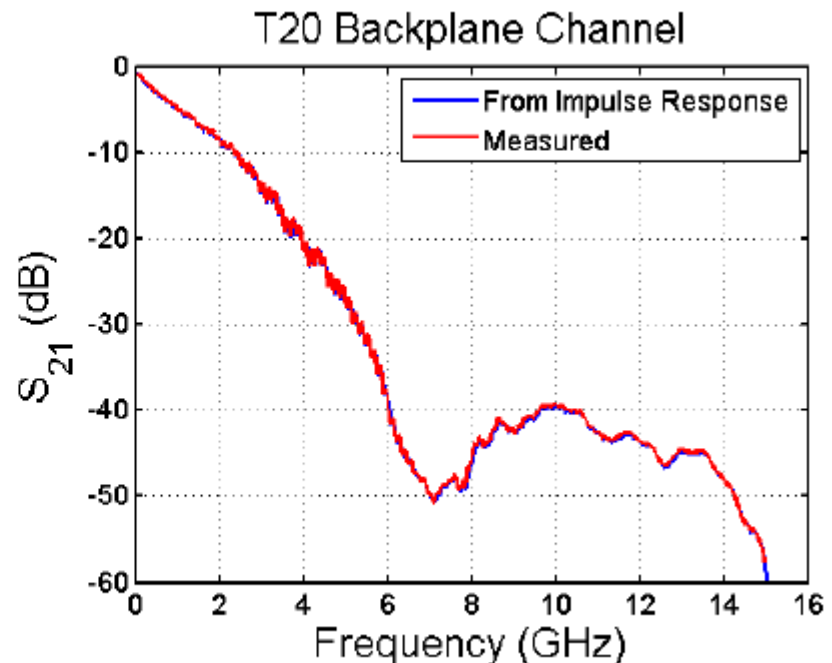
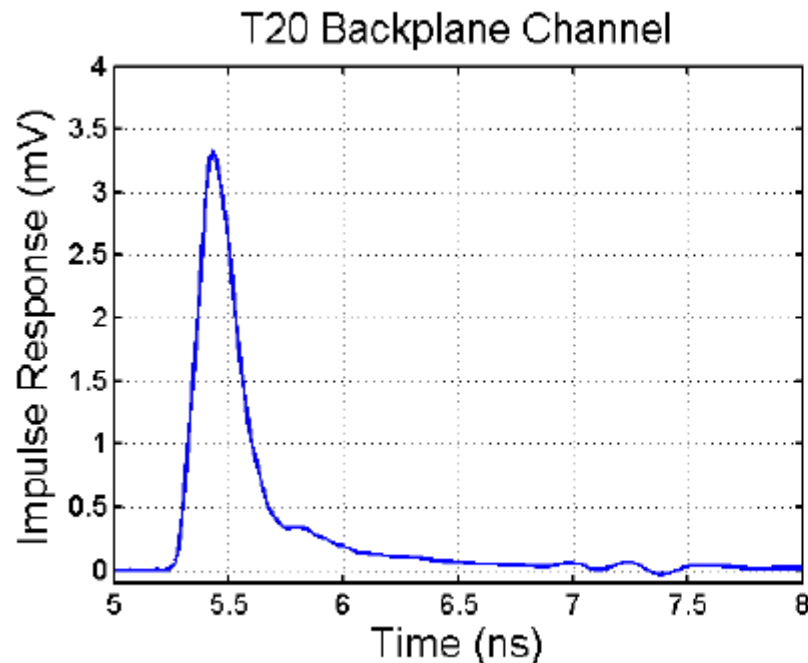
- To improve response resolution, expand frequency axis and “zero pad”.

For 1ps resolution:  
zero pad to +/-500GHz



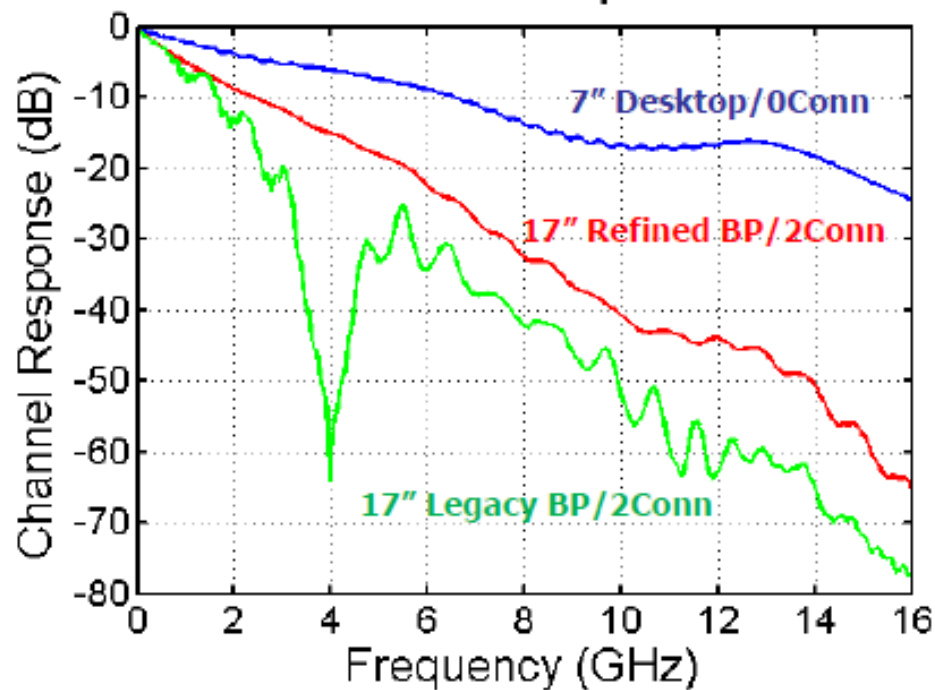
# Impulse Response and S-Parameters (3)

- Now perform ifft to produce impulse response
- Can sanity check by doing fft on impulse response and comparing to measured data

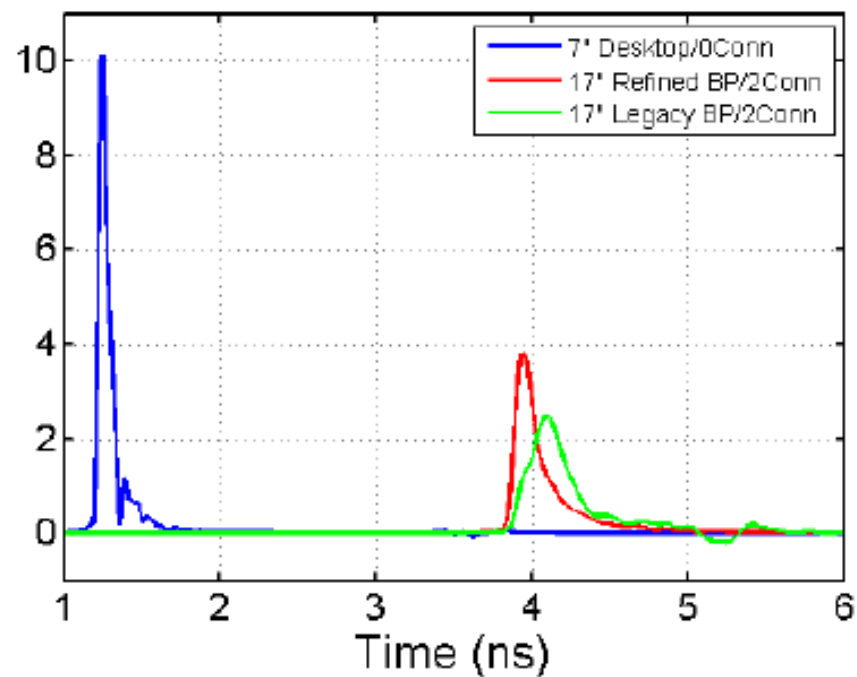


# Different Channels Examples

## Channel Responses

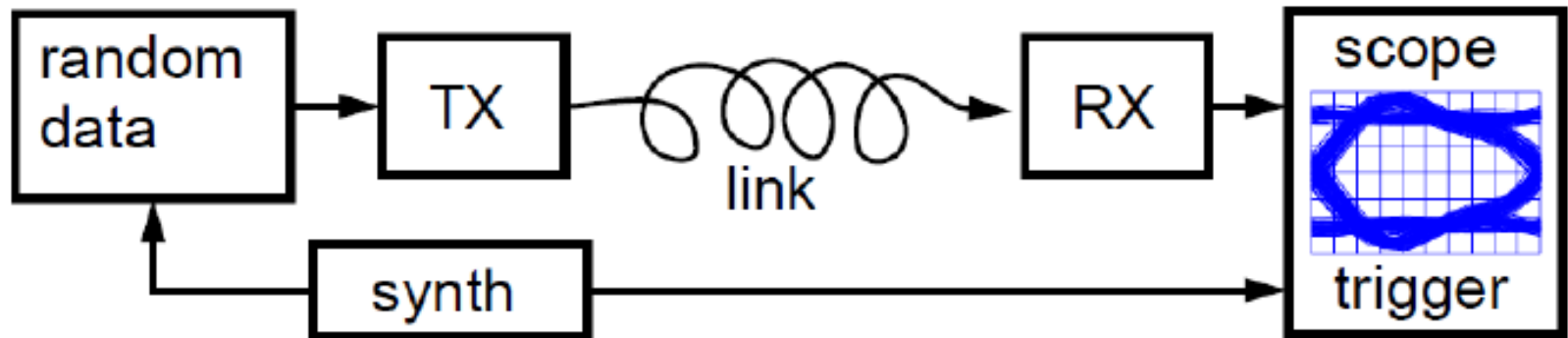


## Channel Impulse Responses





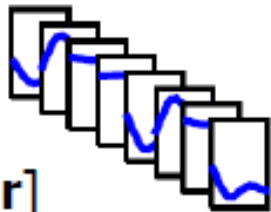
# Eye Diagrams



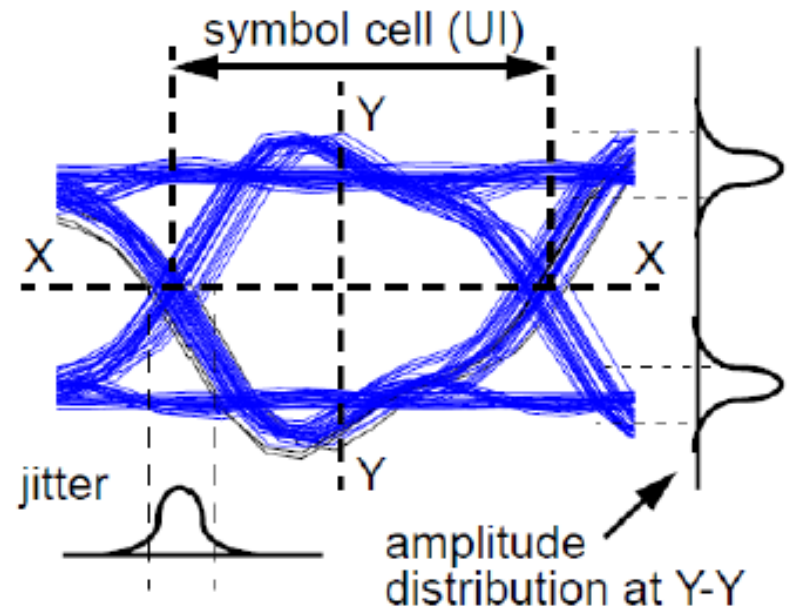
Use a precise clock to chop the data into equal periods



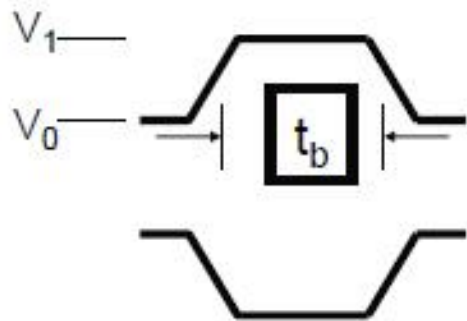
overlay each period onto one plot



**[Walker]**

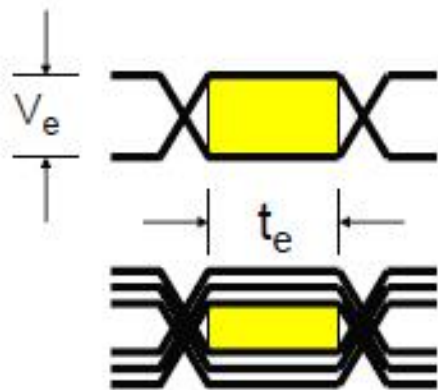


# Eye Diagram Basics



This is a "1"

This is a "0"

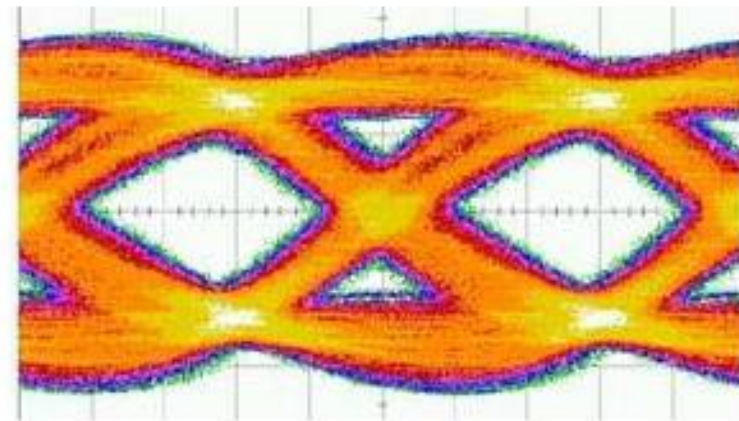


Eye Opening - space between 1 and 0

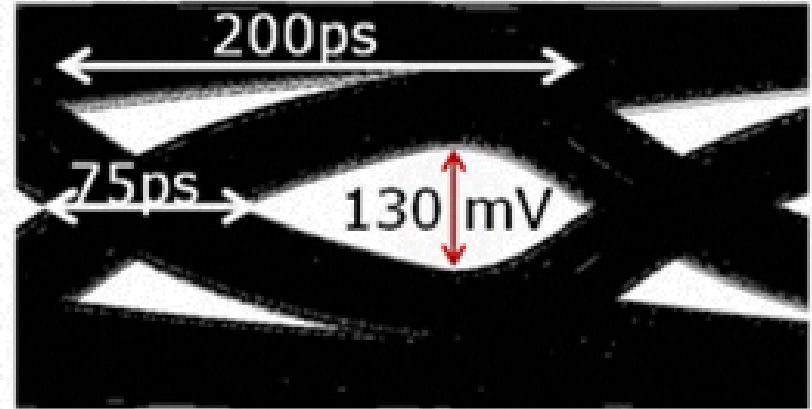
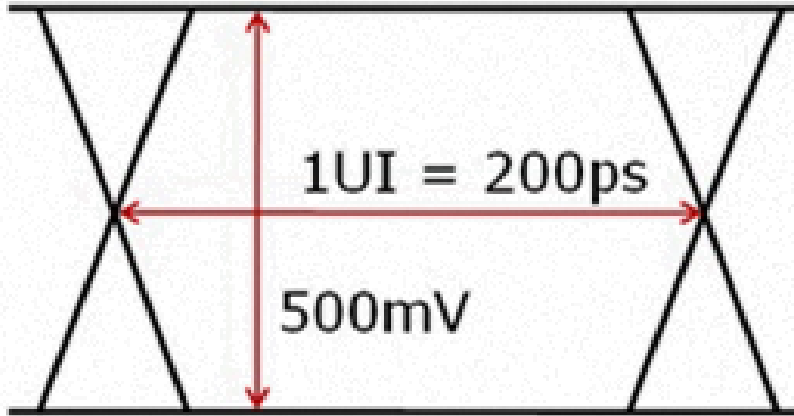
With voltage noise

With timing noise

With Both!



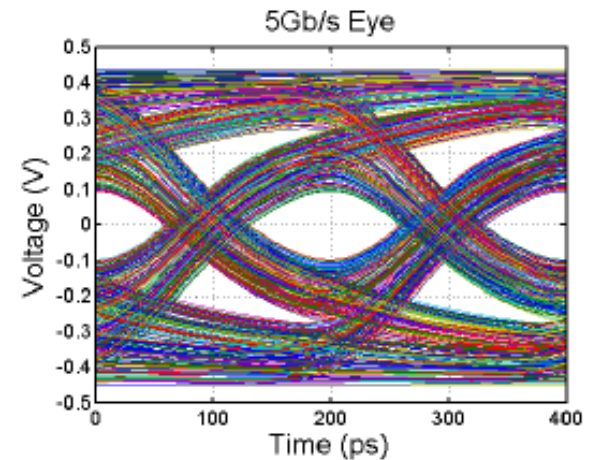
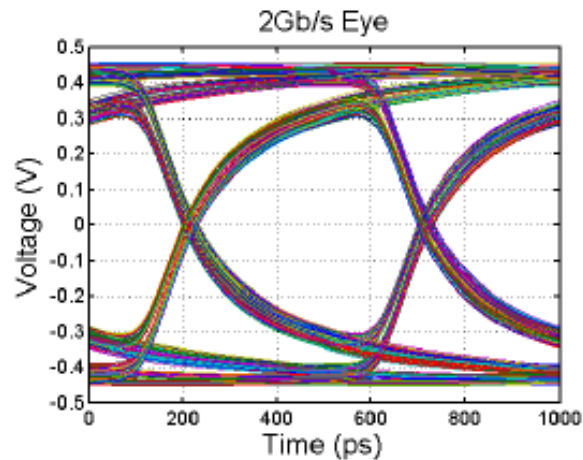
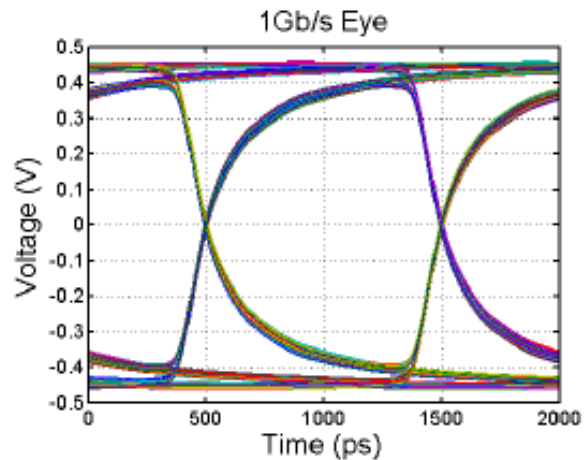
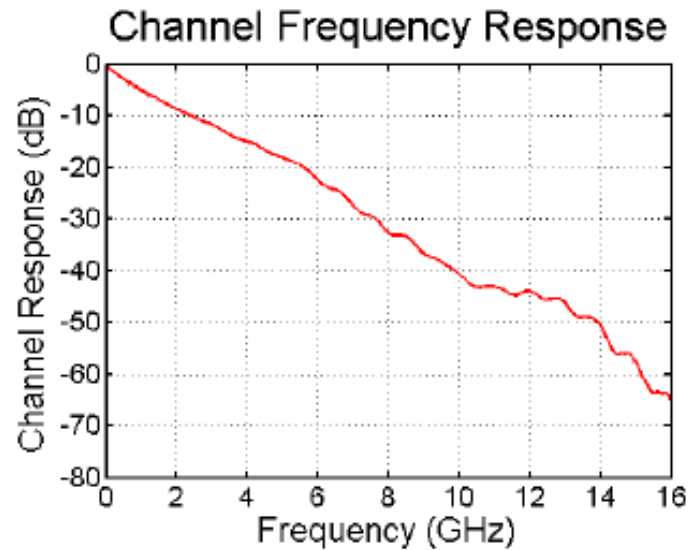
# Loss-Less vs. Lossy Channel



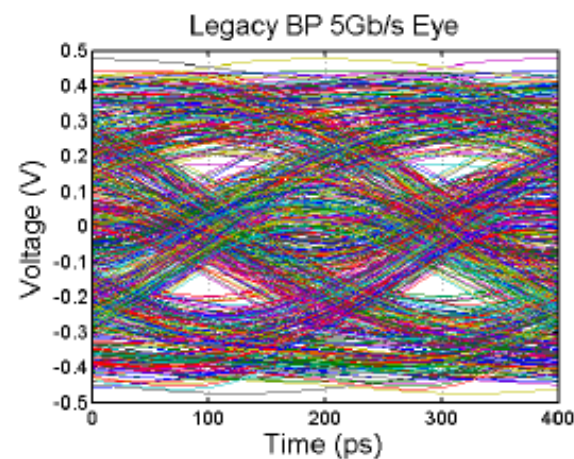
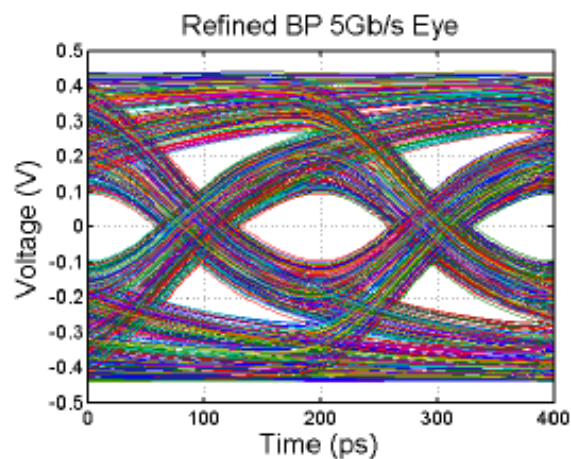
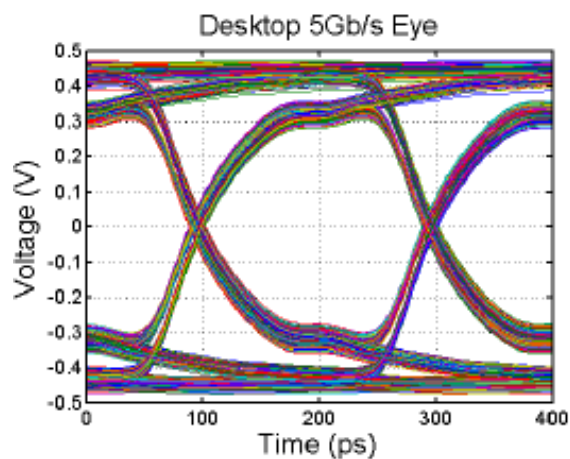
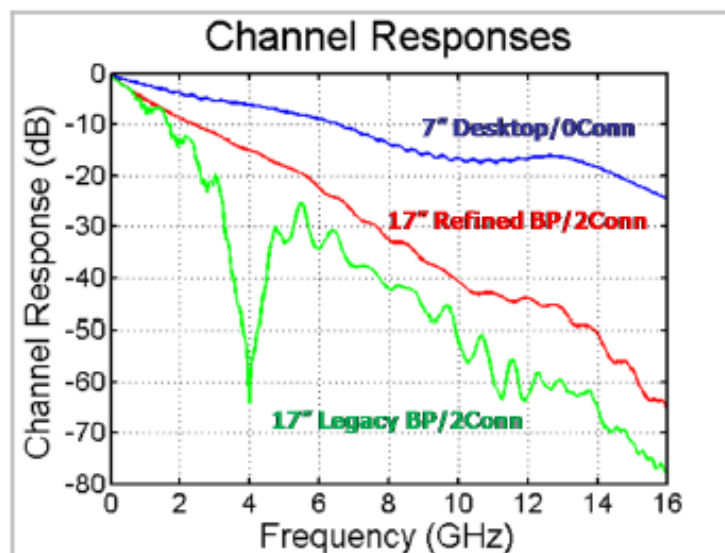
- Loss-less ideal channel
- RX eye = TX eye
- Eye opening = 500 mV
- Clear zero crossing
- No ISI, no jitter
- Reflection and cross-talk further close the eye
- 40'' of FR4
- Data rate = 5 Gb/s
- Effect of attenuation only
- Eye opening = 130 mV
- Zero crossing jitter = 75 ps



# Eye Diagrams vs. Data Rate



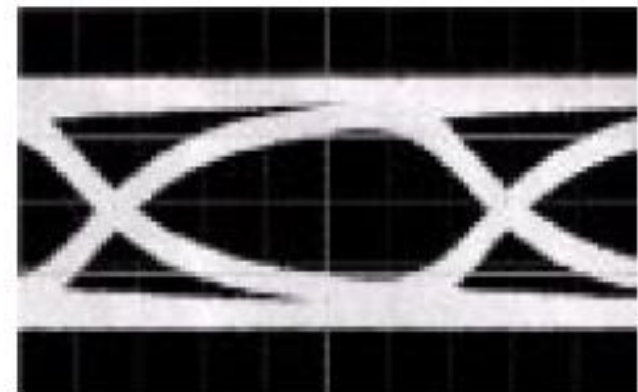
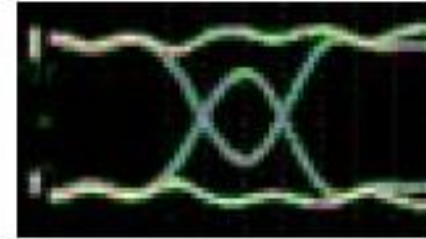
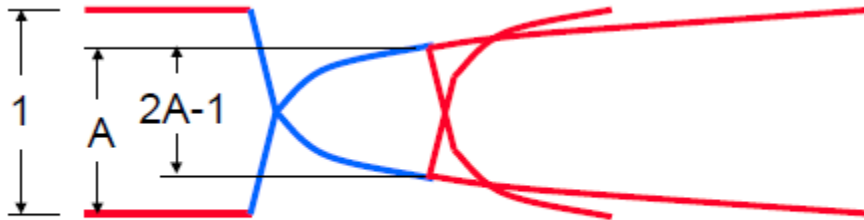
# Eye Diagrams vs. Channel





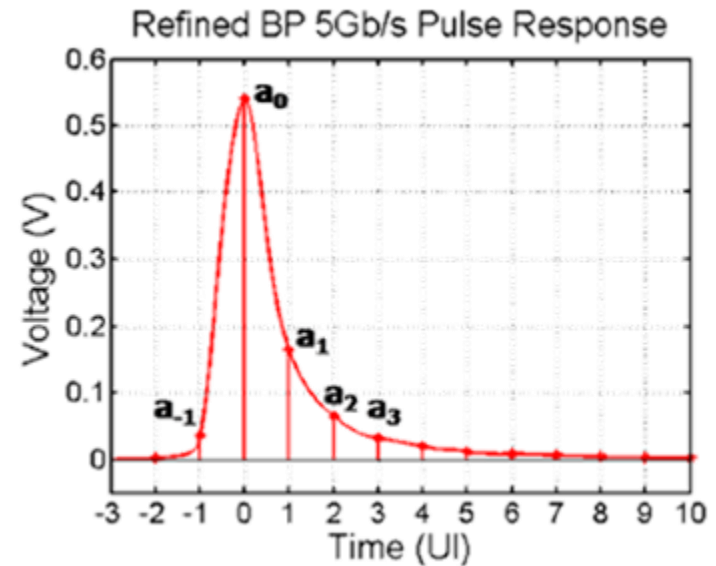
# Attenuation and Eye Opening

- For an attenuation  $A$ , Eye opening is reduced to
$$B = 2A - 1$$
- No eye opening at 50% attenuation
- Significant degradation of margins at lower levels of attenuation



# Estimating the Worst-Case Eye (1)

- Can estimate worst-case eye height and data pattern from pulse response.
- Worst-case “1” is summation of a “1” pulse with all negative non  $k=0$  pulse responses.
- Worst-case “0” is summation of a “0” pulse with all positive non  $k=0$  pulse responses.



$$s_1(t) = y_0^{(1)}(t) + \sum_{\substack{k=-\infty \\ k \neq 0}}^{\infty} y^{(d_k)}(t - kT) \Big|_{y(t-kT) < 0}$$

$$s_0(t) = y_0^{(0)}(t) + \sum_{\substack{k=-\infty \\ k \neq 0}}^{\infty} y^{(d_k)}(t - kT) \Big|_{y(t-kT) > 0}$$

# Estimating the Worst-Case Eye (2)

- Worst case eye height is  $s_1(t) - s_0(t)$ .

$$s(t) = s_1(t) - s_0(t) = (y_0^{(1)}(t) - y_0^{(0)}(t)) + \left( \sum_{\substack{k=-\infty \\ k \neq 0}}^{\infty} y^{(d_k)}(t - kT) \Big|_{y(t-kT) < 0} - \sum_{\substack{k=-\infty \\ k \neq 0}}^{\infty} y^{(d_k)}(t - kT) \Big|_{y(t-kT) > 0} \right)$$

Because  $y_0^{(0)}(t) = -1(y_0^{(1)}(t))$

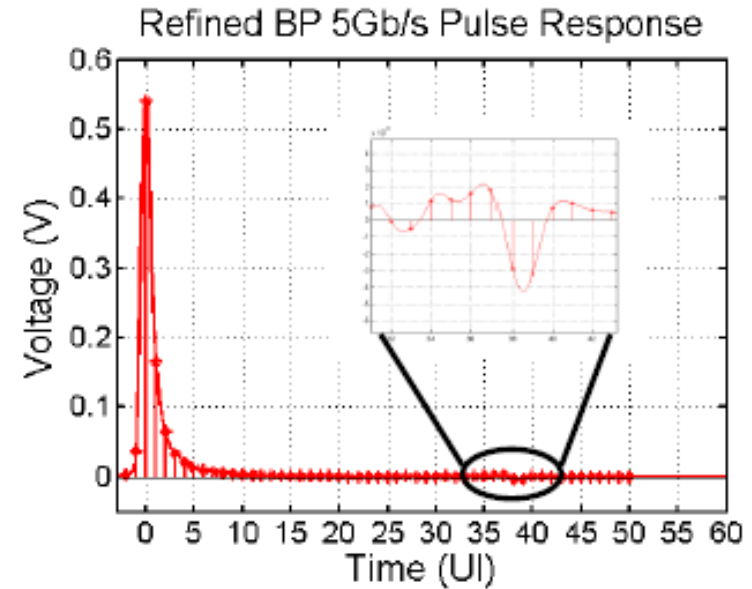
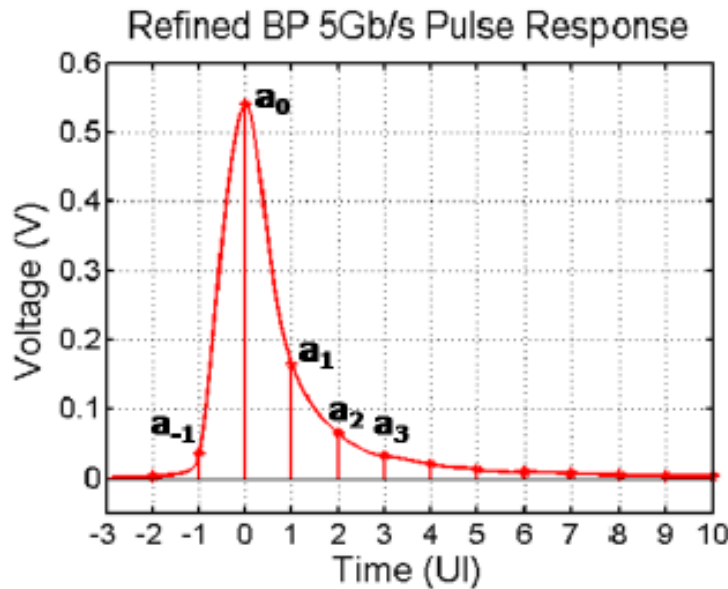
$$s(t) = 2 \left( \underbrace{y_0^{(1)}(t) + \sum_{\substack{k=-\infty \\ k \neq 0}}^{\infty} y^{(1)}(t - kT) \Big|_{y(t-kT) < 0}}_{\text{"1" pulse worst-case "1" edge}} - \underbrace{\sum_{\substack{k=-\infty \\ k \neq 0}}^{\infty} y^{(1)}(t - kT) \Big|_{y(t-kT) > 0}}_{\text{"1" pulse worst-case "0" edge}} \right)$$

- If symmetric "1" and "0" pulses, then only positive pulse response is needed.





# Worst-Case Eye Example 1

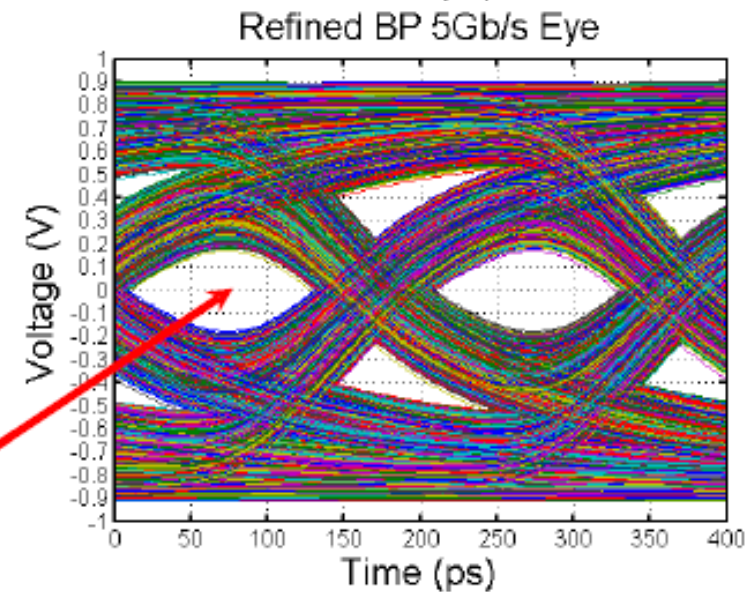


$$y_0^{(1)}(t) = 0.540$$

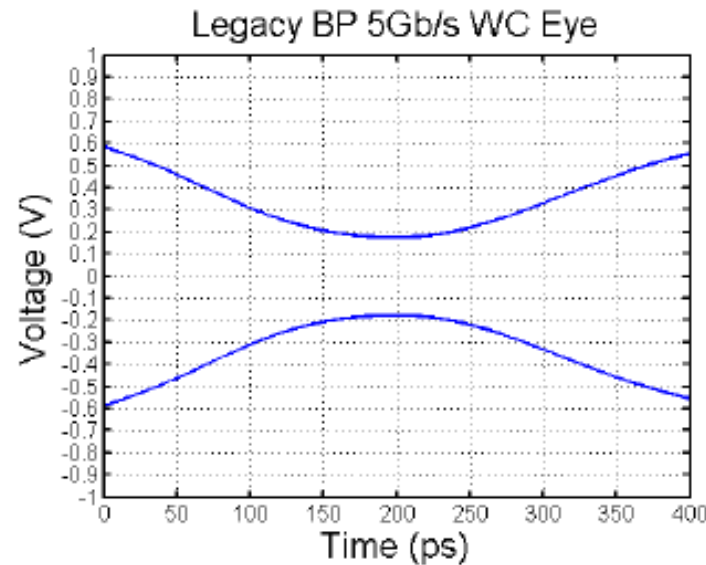
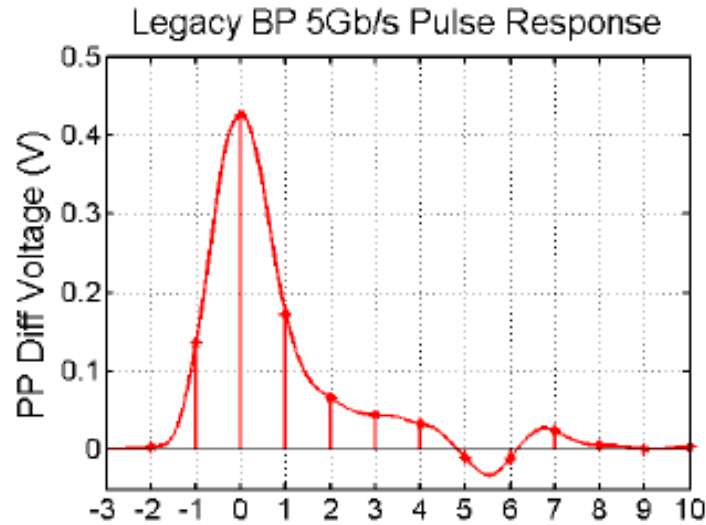
$$\sum_{\substack{k=-\infty \\ k \neq 0}}^{\infty} y^{(1)}(t - kT) \Big|_{y(t-kT) < 0} = -0.007$$

$$\sum_{\substack{k=-\infty \\ k \neq 0}}^{\infty} y^{(1)}(t - kT) \Big|_{y(t-kT) > 0} = 0.389$$

$$s(t) = 2(0.540 - 0.007 - 0.389) = 0.288$$



# Worst-Case Eye Example 2

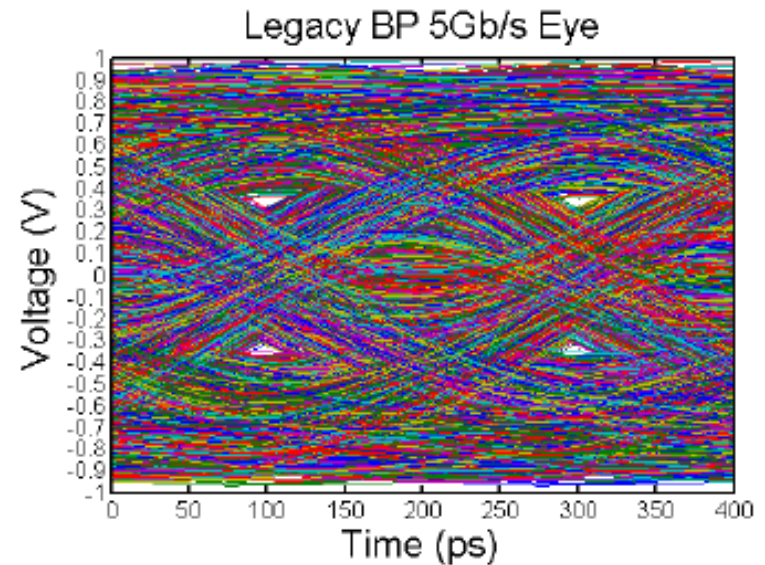


$$y_0^{(1)}(t) = 0.426$$

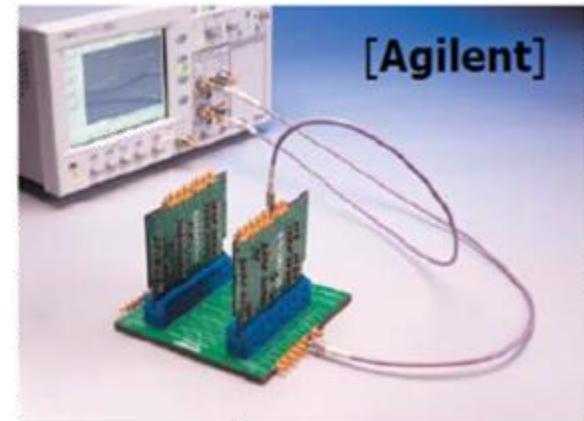
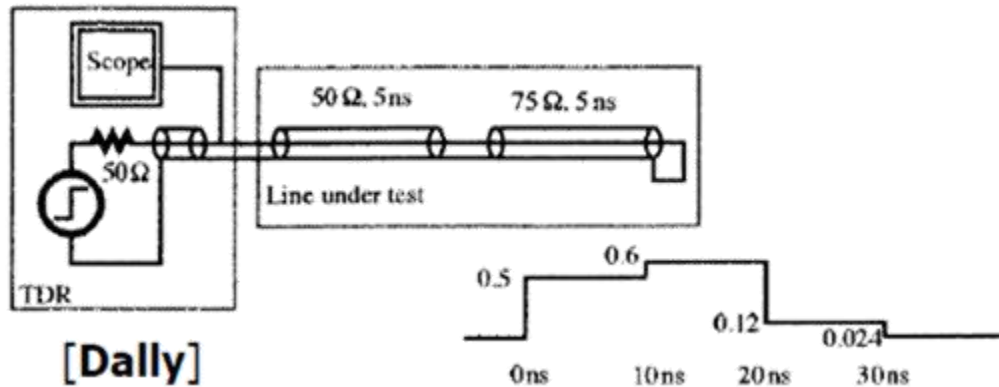
$$\sum_{\substack{k=-\infty \\ k \neq 0}}^{\infty} y^{(1)}(t - kT) \Big|_{y(t-kT) < 0} = -0.053$$

$$\sum_{\substack{k=-\infty \\ k \neq 0}}^{\infty} y^{(1)}(t - kT) \Big|_{y(t-kT) > 0} = 0.542$$

$$s(t) = 2(0.426 - 0.053 - 0.542) = -0.338$$



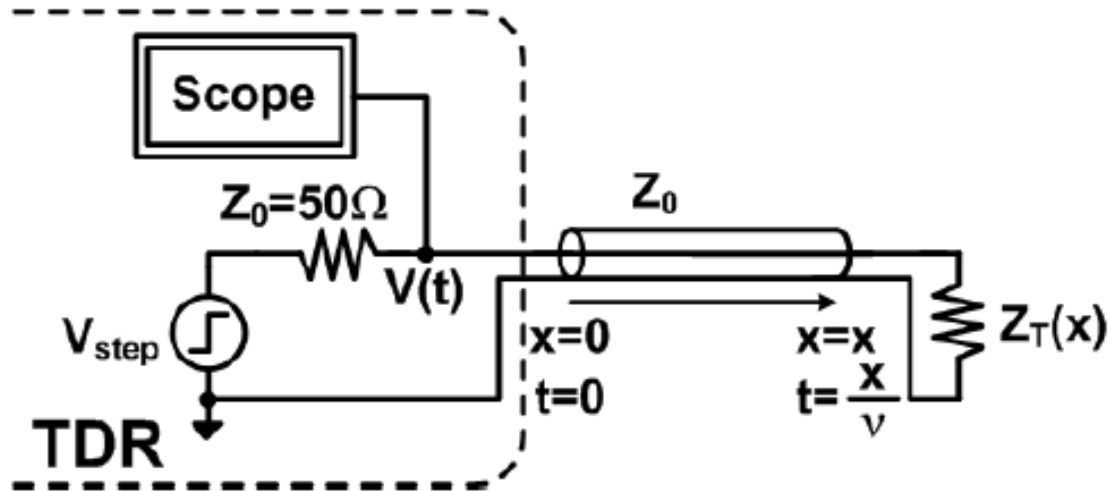
# Time-Domain Reflectometer (TDR)



- TDR consists of a fast step generator and a high-speed oscilloscope
- TDR operation
  - Outputs fast voltage step onto channel
  - Observe voltage at source, which include reflections
  - Voltage magnitude can be converted to impedance
  - Impedance discontinuity location can be determined by delay
- Only input port access to characterize channel (vs. VNA)



# TDR Impedance Calculation



$$k_r(t) = \frac{V_r(t)}{V_i} = \frac{Z_T(t) - Z_0}{Z_T(t) + Z_0}$$

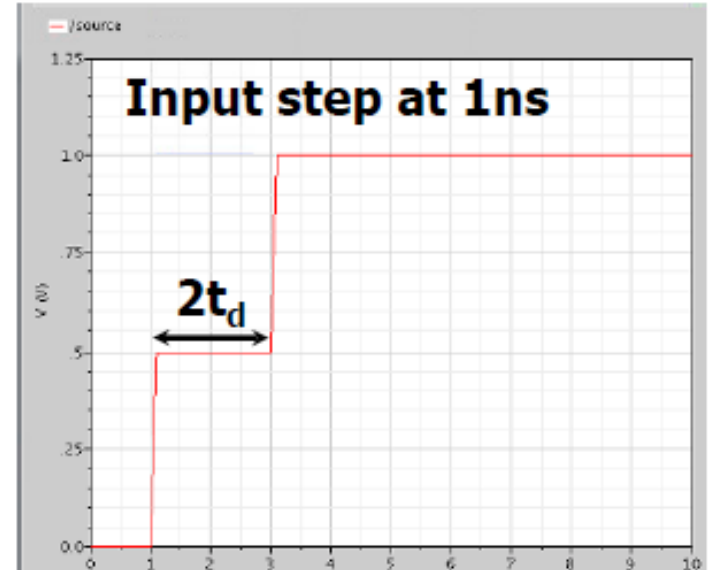
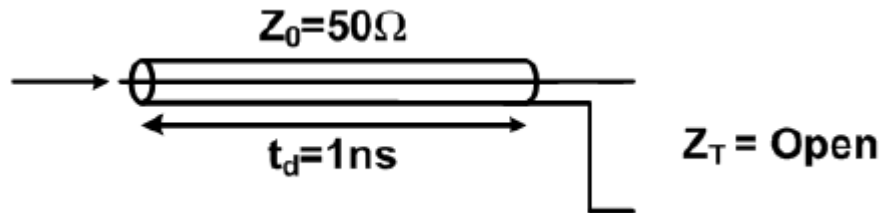
$$Z_T(t) = Z_0 \left( \frac{1 + k_r(t)}{1 - k_r(t)} \right) = Z_0 \left( \frac{V_i + V_r(t)}{V_i - V_r(t)} \right) = Z_0 \left( \frac{V(t)}{2V_i - V(t)} \right)$$

$$\text{If } V_{\text{STEP}} = 1V \Rightarrow V_i = 0.5V$$

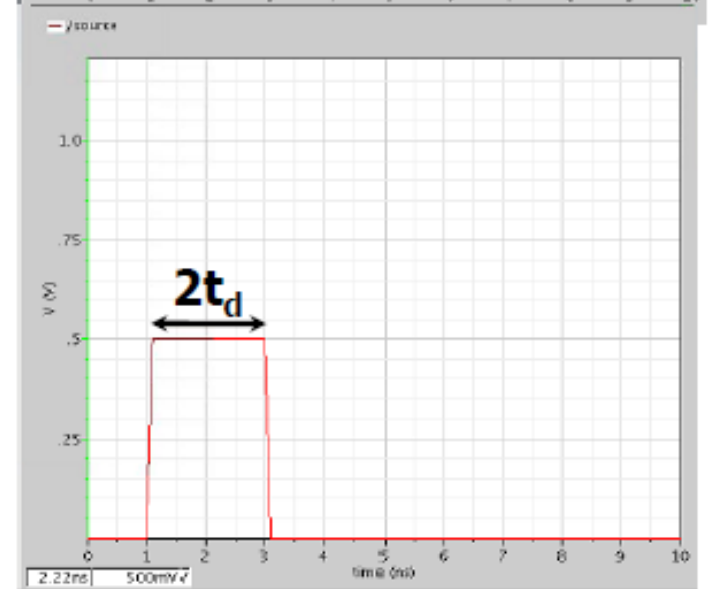
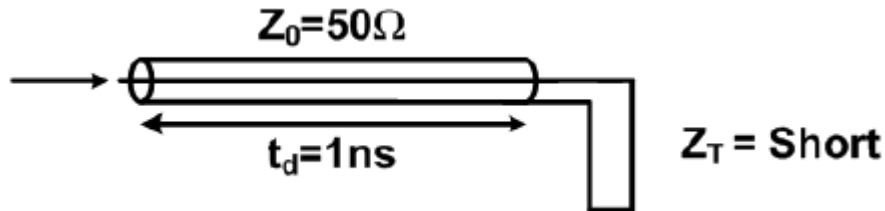
$$Z_T(t) = Z_0 \left( \frac{V(t)}{1V - V(t)} \right) \quad Z_T(x) = Z_T \left( t = \frac{2x}{v} \right)$$

# TDR Waveforms (Open & Short)

- Open termination

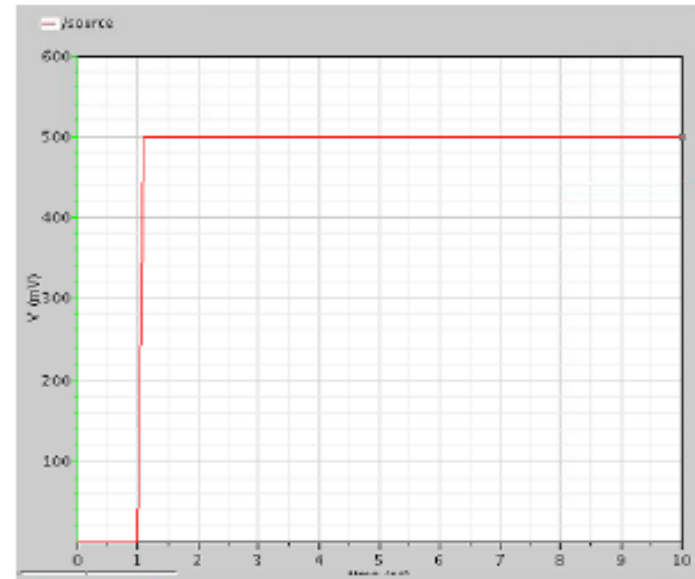
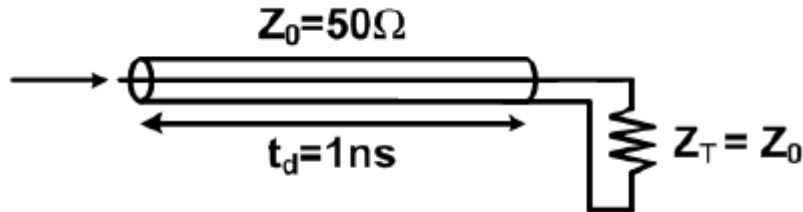


- Short termination

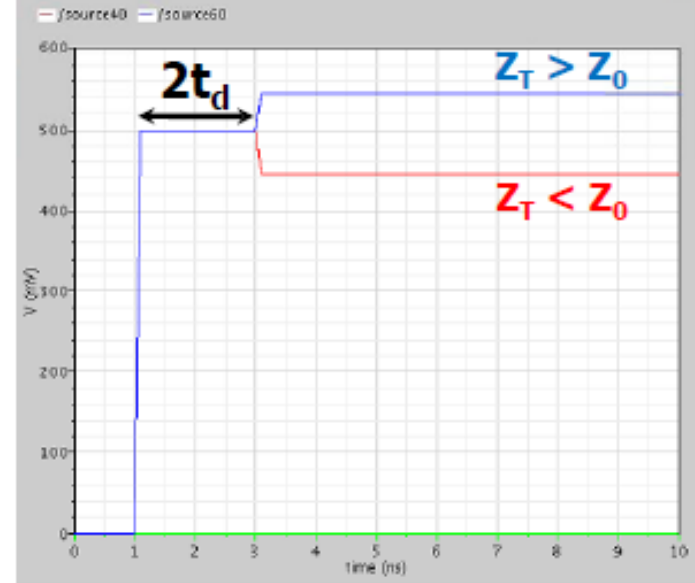
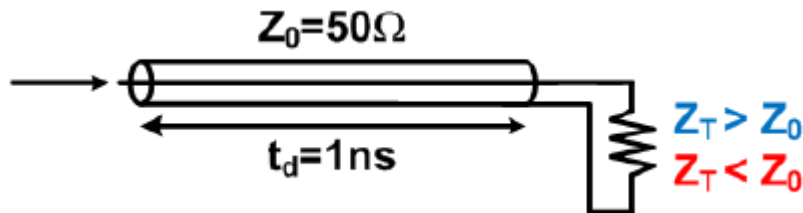


# TDR Waveforms (Matched & Unmatched)

- Matched termination

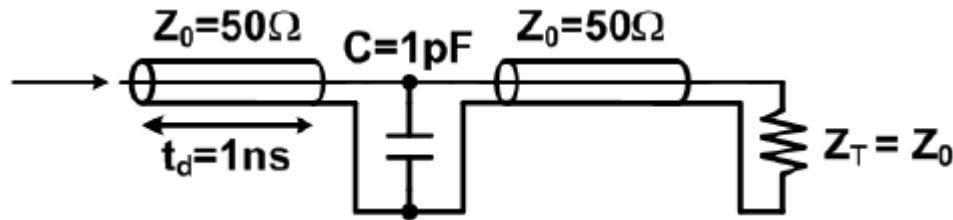


- Unmatched termination

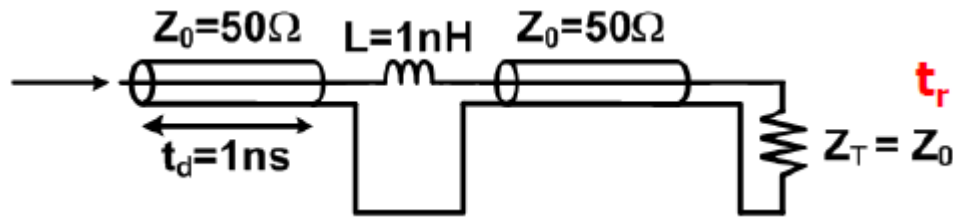


# TDR Waveforms (C & L Discontinuity)

- Shunt C discontinuity



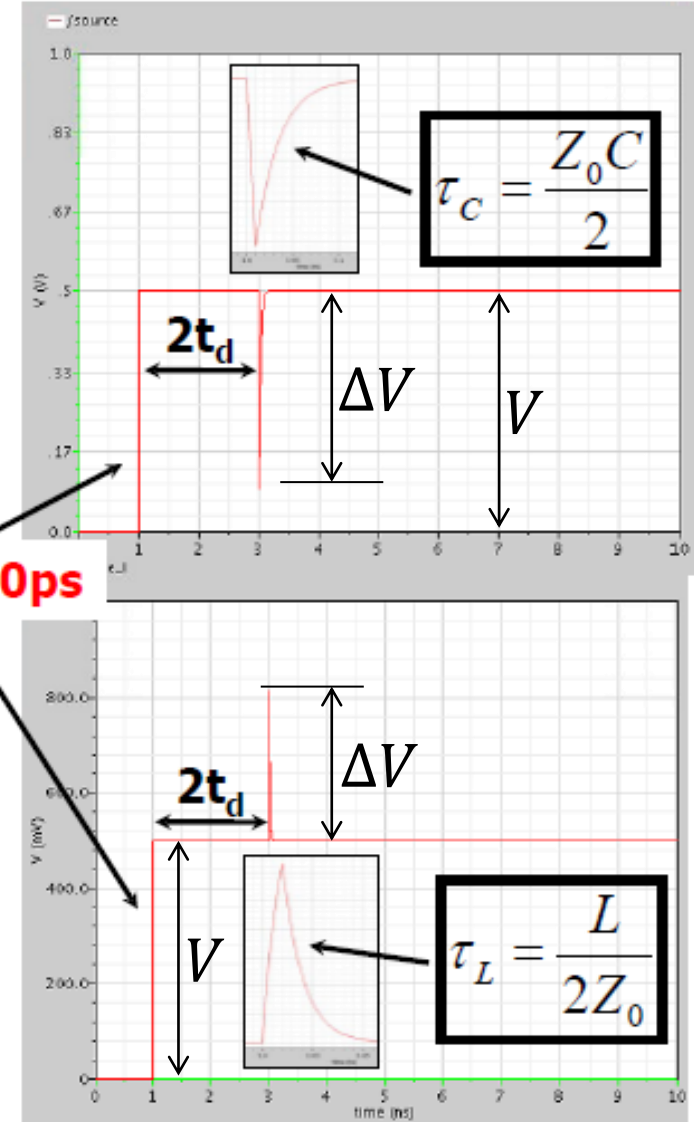
- Series L discontinuity



- Spike depends on rise time

$$\frac{\Delta V}{V} = \left( \frac{\tau}{t_r} \right) \left[ 1 - e^{\left( -\frac{t_r}{\tau} \right)} \right]$$

$t_r = 10\text{ps}$





# Rise-Time Degradation

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- **Upstream elements (Ls & Cs) low-pass the signal resulting in a longer rise-time.**
- **This affects the reflections from down-stream elements.**
  - Slow rising edge
  - Spread out response
  - L & C responses do not go full swing.
- **This makes it**
  - Hard to extract L and C values.
  - Impossible to measure very small discontinuities.
    - But if the TDR cannot see them, neither can the signal.





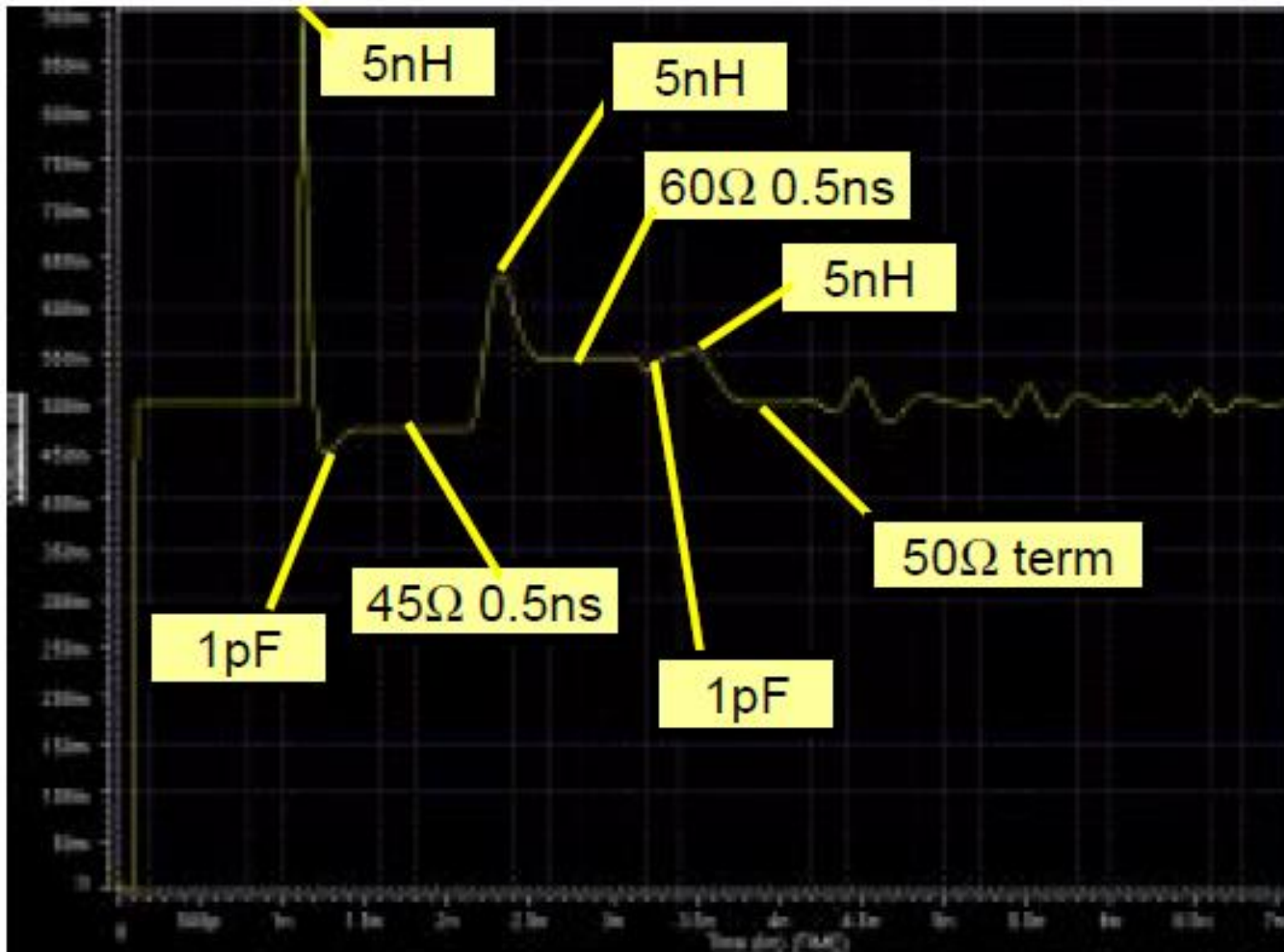
# Extraction Procedure

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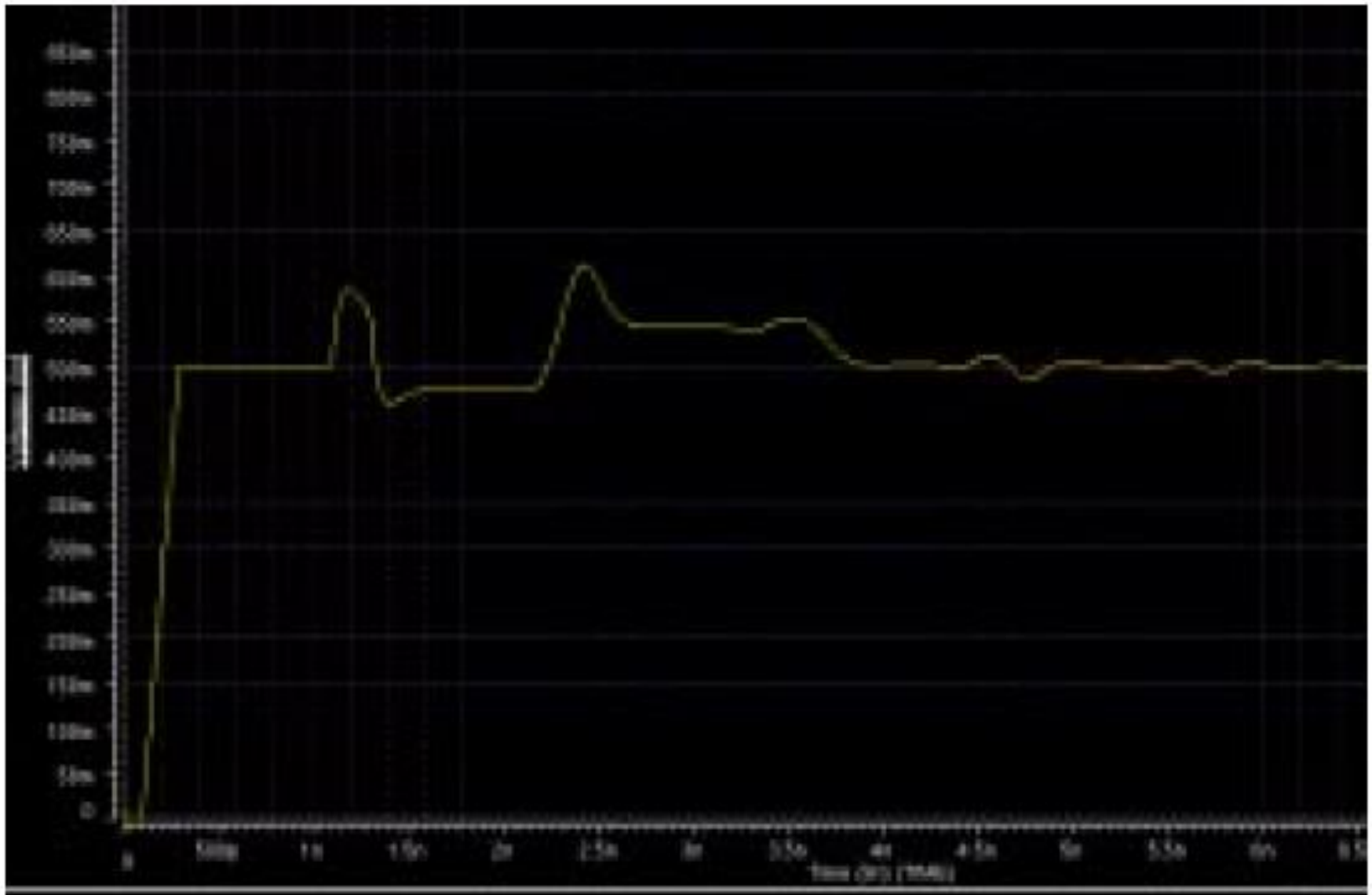
- **Identify regions of the TDR plot as**
  - Flat region – transmission line
  - Bump up – inductor
  - Bump down – capacitor
- **Starting at source**
  - Determine value of  $Z$  &  $t_d$ ,  $L$ , or  $C$  for nearest element.
  - Simulate to validate and determine new  $t_r$ .
  - Iterate as needed to get the value right.
  - Move on to the next element.
- **There is no need for models with more resolution than the fastest rise time.**



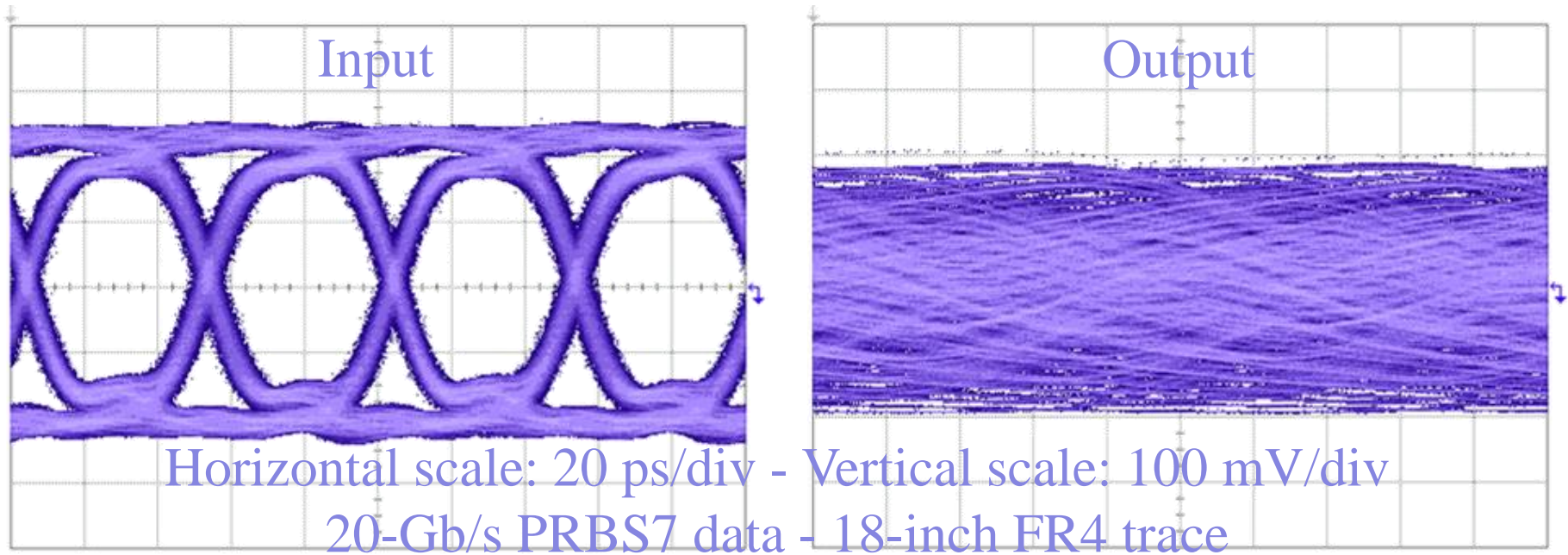
# Example TDR Trace



# Same Waveform with 200 ps Edge



# Channel Summary



- **Untreated received eye is closed, or almost closed**
- **How can it be opened?**
  - Characterize channel & compensate for it at TX/RX.
  - Use signaling schemes that best match channel. (NRZ)
  - Use coding to relax constraints. (8b/10b)
- **How to quantize performance?**



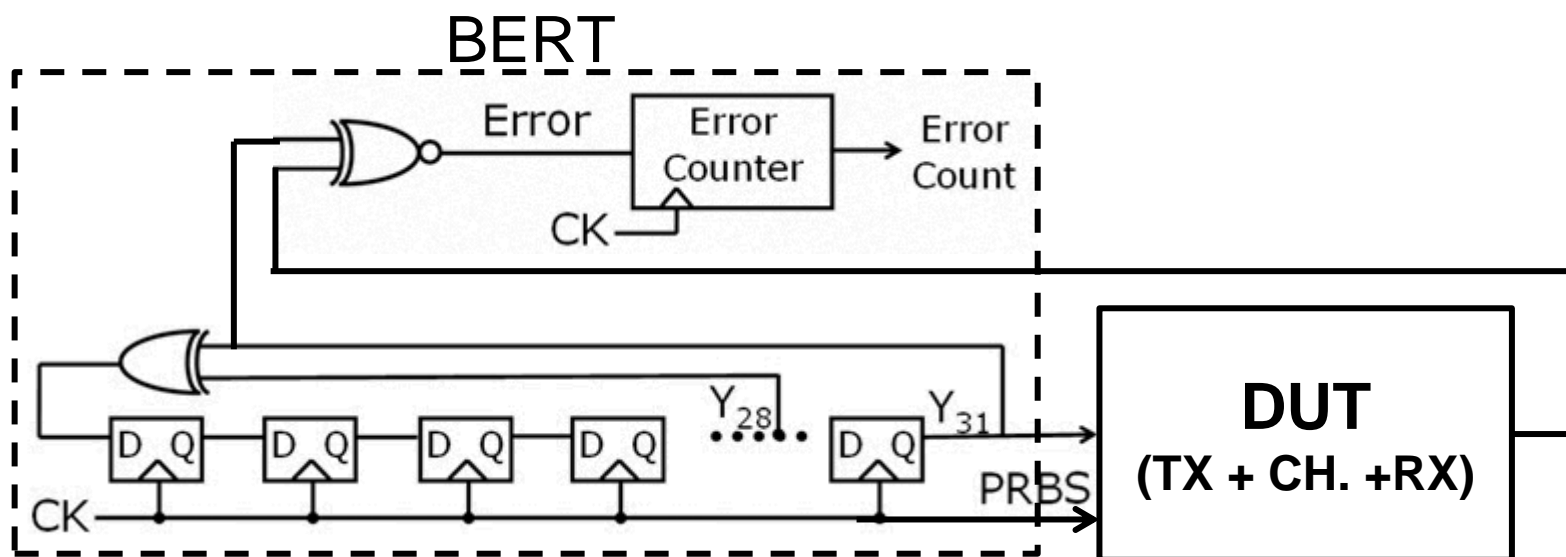
# Bit-Error Rate (BER)

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- System overall performance is best described by BER.
- $\text{BER} = \# \text{ of erroneous bits} / \text{total number of bits}$ .
- At multiple Gb/s rates, the BER requirement for most I/O communication standards is  $10^{-12}$  or smaller.
- BER are measured using BERT.
- BERT consists of a pattern generator and error detector.
- Pseudo random binary sequence (PRBS) is the most common bit sequence used in BERTs to mimic a truly-random sequence.
- PRBS are generated by linear-feedback shift registers (LFSR).

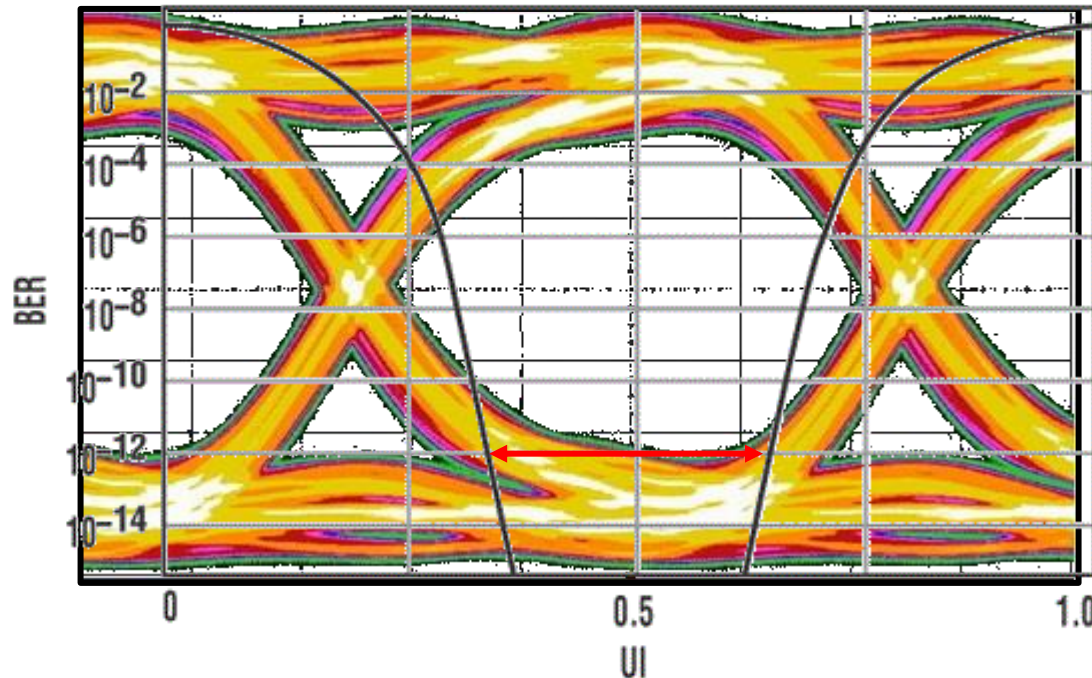


# Link Performance Using BERT



N	Polynomial	Period	N	Polynomial	Period
31	$Y^{31} + Y^{28} + 1$	$2^{31} - 1$	7	$Y^7 + Y^6 + 1$	$2^7 - 1$
23	$Y^{23} + Y^{18} + 1$	$2^{23} - 1$	3	$Y^3 + Y^1 + 1$	$2^3 - 1$
15	$Y^{15} + Y^{14} + 1$	$2^{15} - 1$			

# Bathtub Curve



- Shows the BER as a function of the sampling time.
- Determines the horizontal eye opening of the eye diagram.
- Heavily dependent on the system jitter.
- How can we predict this from the beginning?





# Traditional Approach

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- **Borrowed from computer systems**
  - Built to be “error free” ( $10^{-20}$ )
  - Worst-case analysis
- **Voltage/Time (VT) Budget**
  - Also called link Budget
  - Deterministic (Bounded) error sources [Cross-talk, residual-ISI, reflections, supply and reference noise, TX offsets, RX offsets and sensitivity] add in the same direction.
  - Random (Unbounded) error sources [Thermal and flicker noise] add in rms.
  - V & T completely separated.

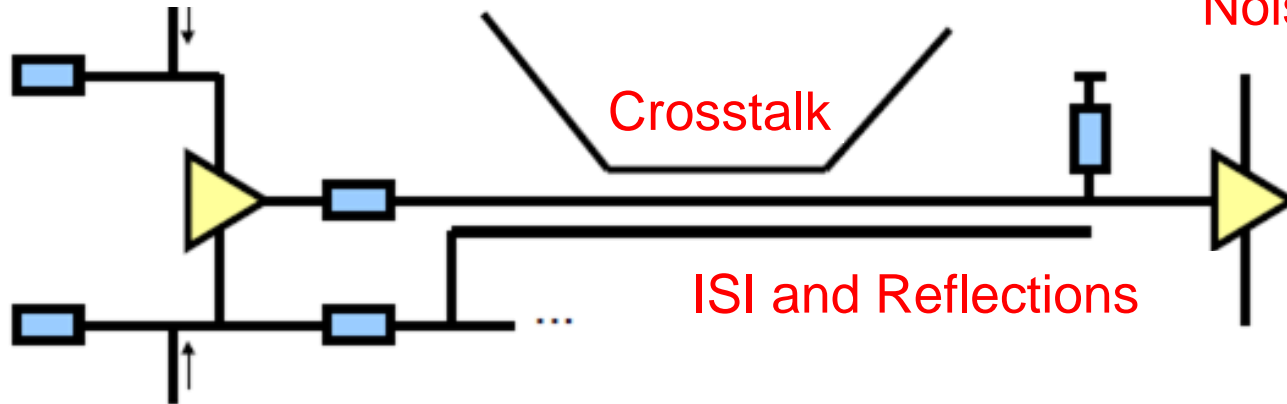




# Traditional Voltage Budget Example

Transmitter Bounded  
Noise

Receiver Bounded  
Noise



- $BER = \frac{1}{2} \operatorname{erfc} \left( \frac{h}{\sqrt{2}\sigma} \right)$
- $h = \text{Swing} - \sum DN$
- **Swing determined by residual ISI (worst case eye)**
- **DN = deterministic noise**
- **$\sigma$  is obtained by rms addition.**

Signal Swing		400	mV
Vni	Rx offset + sensitivity	50	mV
	Uncancelled PS noise	20	mV
	Total Vni	70	mV
Kn	Crosstalk	10	%
	Reflections	10	%
	Total	20	%
	KnVs	80	mV
	Vn = Vni + KnVs	150	mV

# Issues with Traditional Approach

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- **Worst-case analysis is not realistic, especially with large number of residual-ISI taps.**
- **Voltage and timing cannot be treated separately for modern links.**
- **Modern approach**
  - Uses noise and ISI statistics
  - Integrates timing noise with voltage noise
  - Needs mapping from time to voltage



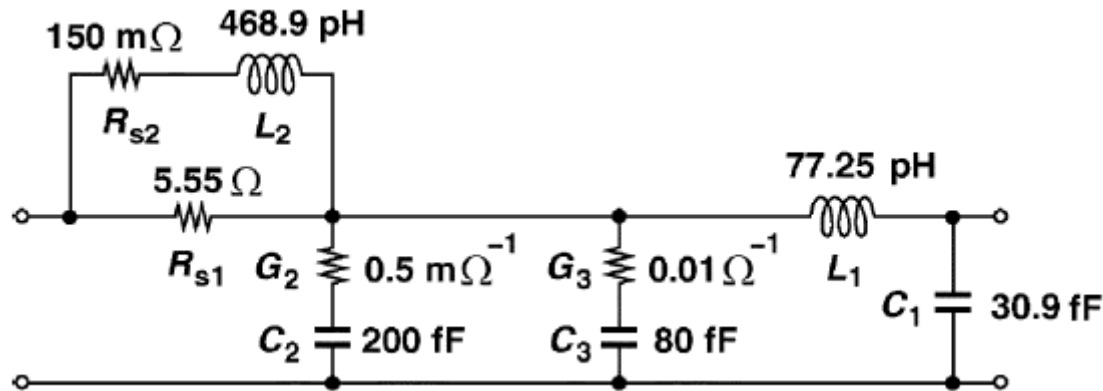
# Assignment 1

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- **Assignment is due on 16/03/19 at 10 AM.**
- **Use the through channel s-parameters “channel.s4p” to provide the following plots:**
  - AC magnitude and phase (i.e.,  $s_{21}$ ) from 0 Hz to 20 GHz.
  - Time-domain pulse response at 8 Gb/s indicating symbol-spaced sample values.



# Assignment 1 (Contd.)



- The figure shown is a model for a 1-inch FR4 trace that can be cascaded for longer traces.
- Provide the input and output eye diagram for a 6-inch FR4 trace using an 8-Gb/s PRBS source with 0.5 V<sub>pp</sub> swing.
- Estimate the worst-case eye opening and compare it to the simulated eye.

